

Uncertainty Quantification for Electronic System Design

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Outline



Dynamic Steady-State Temperature Analysis
and Reliability Optimization



Statistical Analysis of Process Variation
Based on Indirect Measurements



Probabilistic Analysis of Power and
Temperature Under Process Variation



Temperature-Centric Reliability Analysis
and Optimization Under Process Variation

Outline



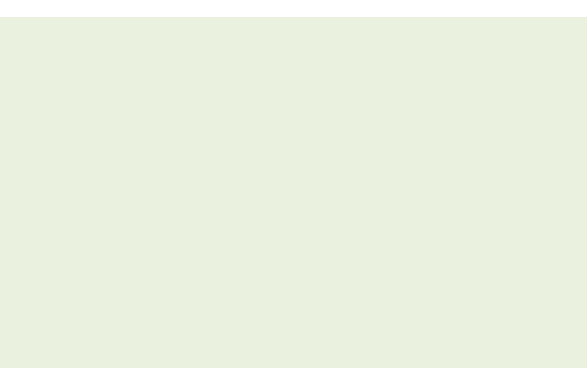
Dynamic Steady-State Temperature Analysis
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Statistical Analysis of Process Variation
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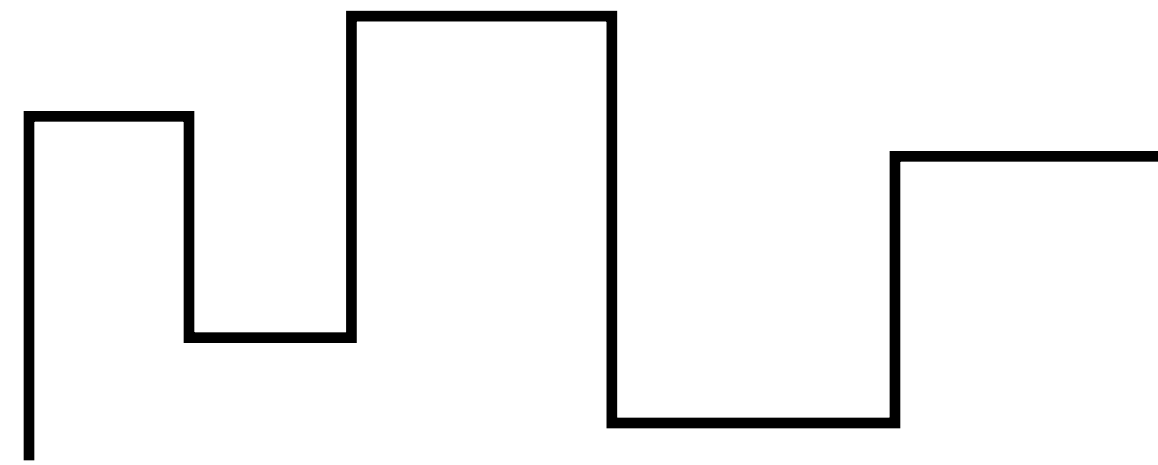
Probabilistic Analysis of Power and
Temperature Under Process Variation



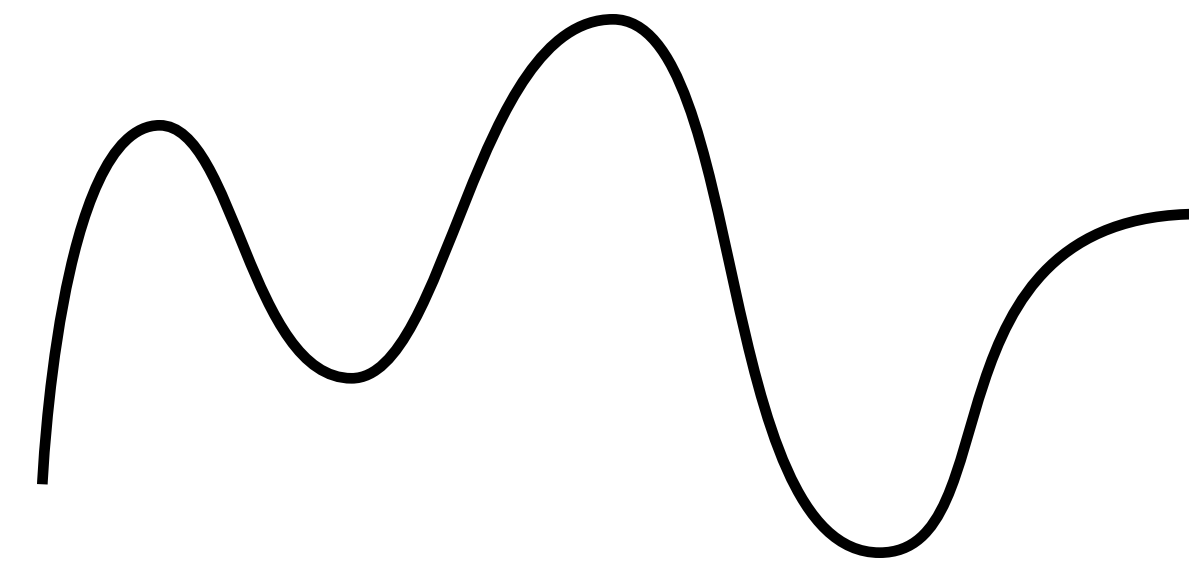
Temperature-Centric Reliability Analysis
and Optimization Under Process Variation

Temperature Analysis

* Transient



Power



Temperature

Temperature Analysis

- * Static steady state

•

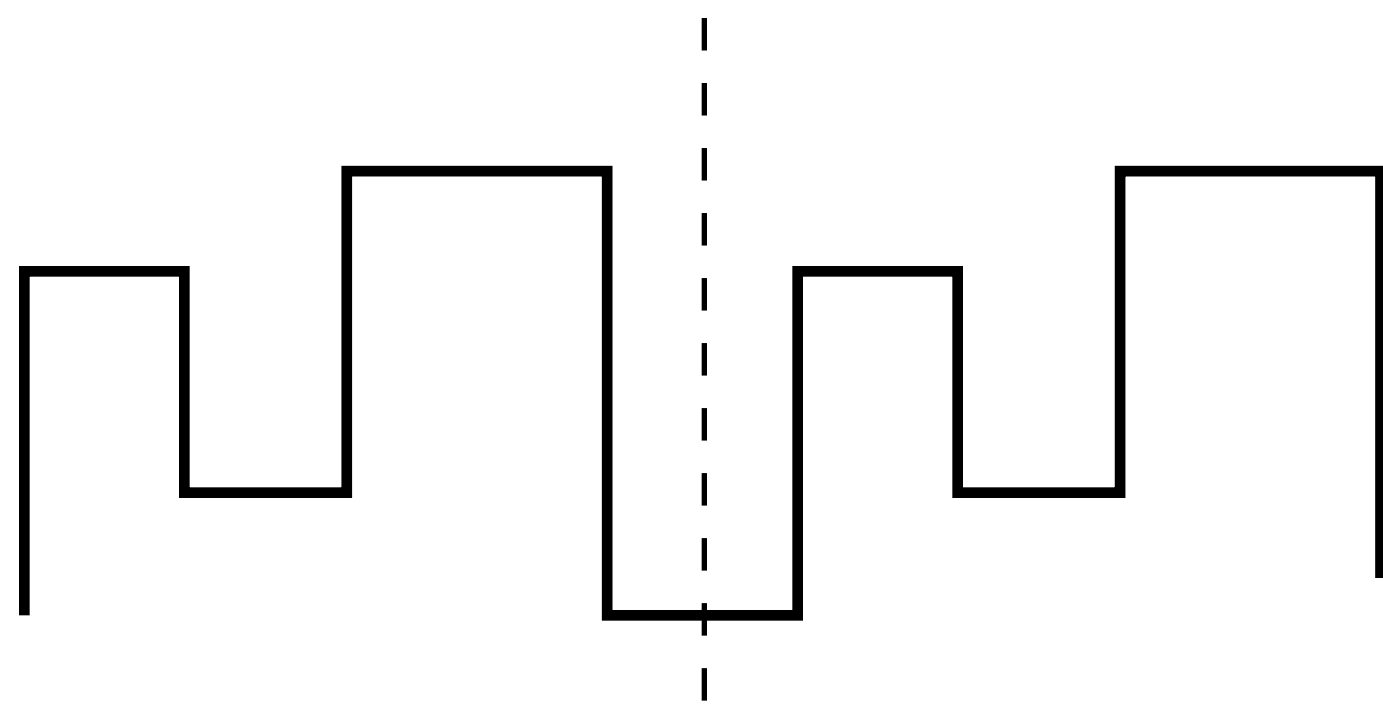
Power

•

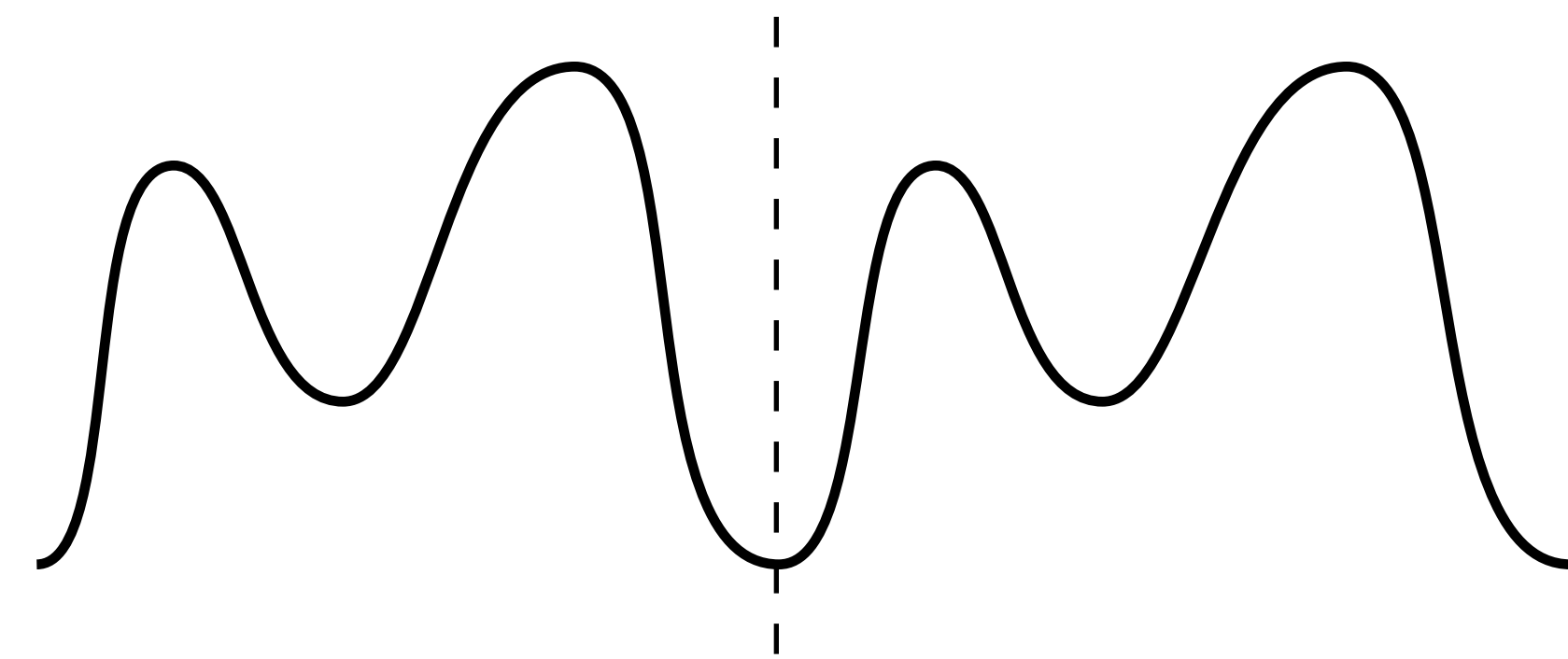
Temperature

Temperature Analysis

- * Dynamic steady state



Power



Temperature

Our Goal

Given:

- * Multiprocessor system
- * Periodic dynamic power profile

Find:

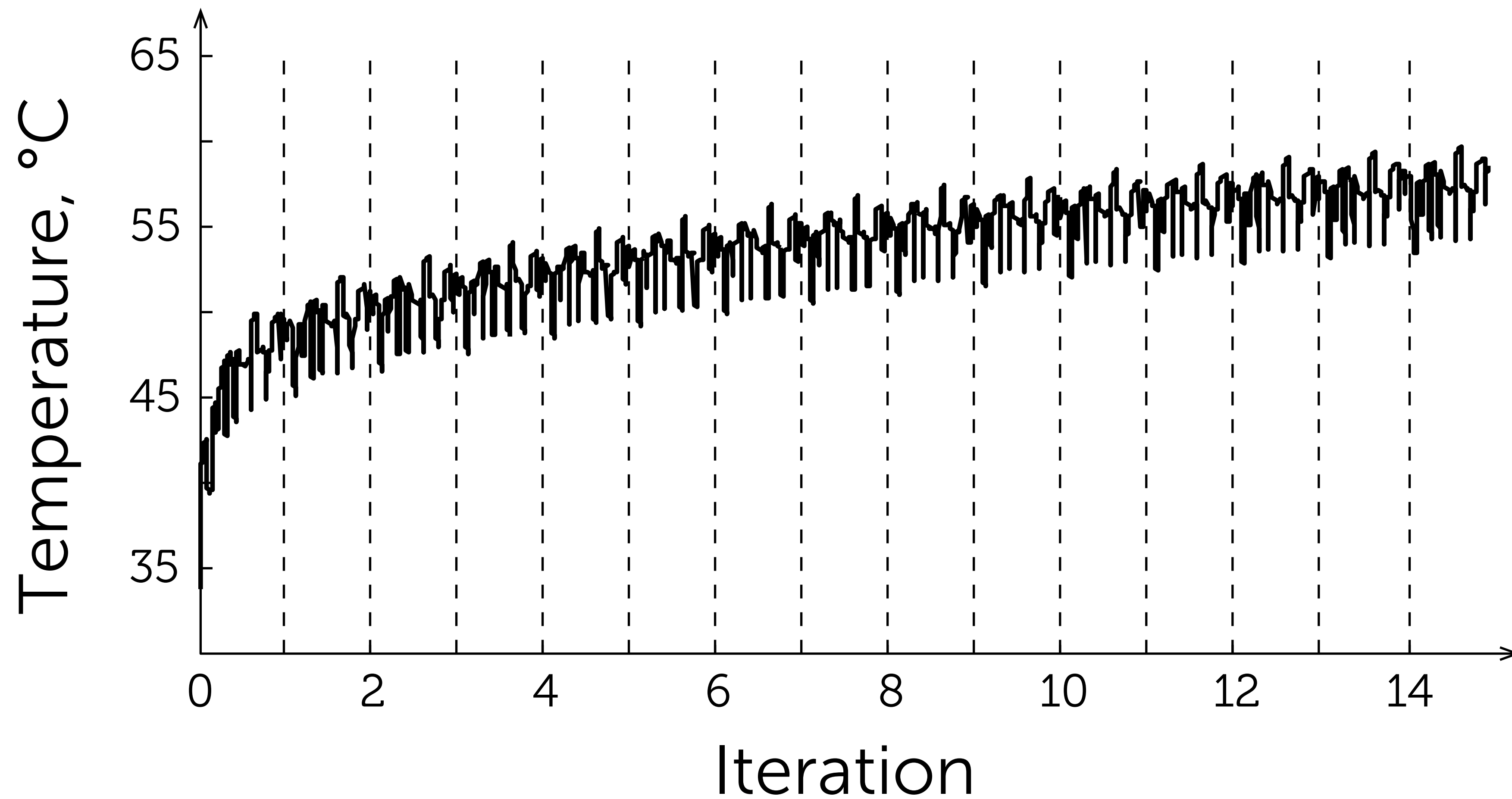
- * Dynamic steady-state temperature profile

Such that:

- * Accurate and fast

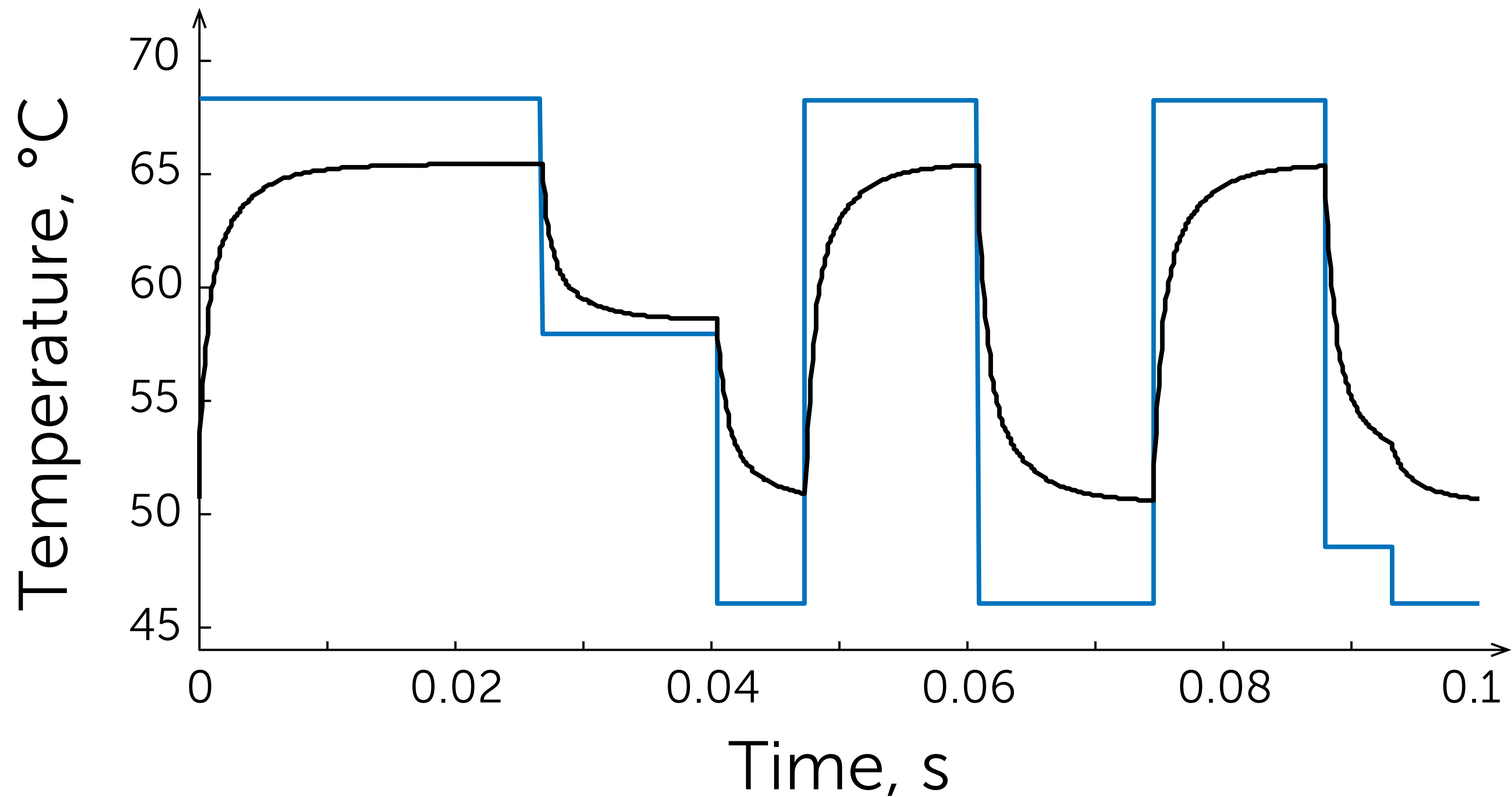
Alternatives

- * Repetitive transient analysis



Alternatives

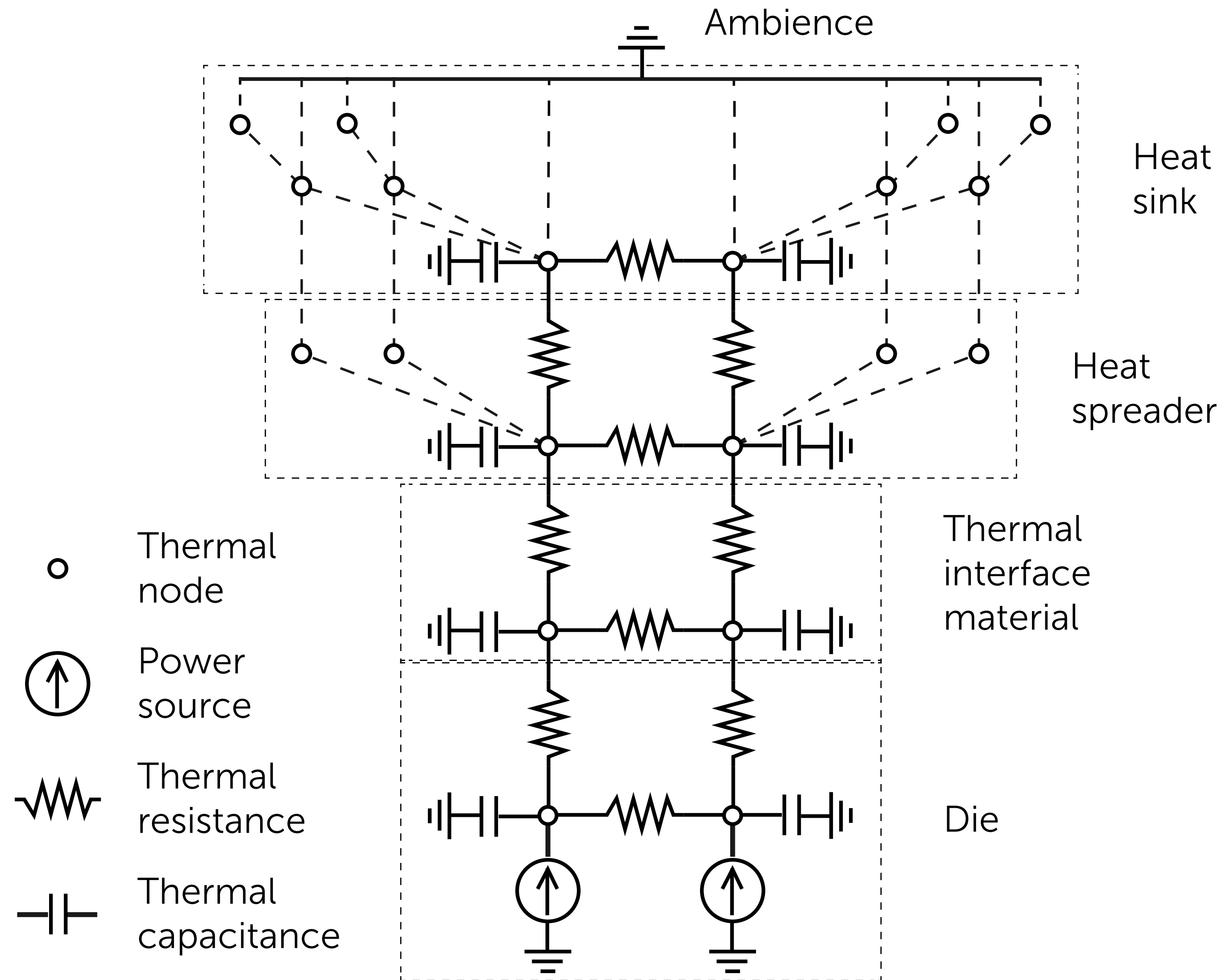
- * Static-steady-state approximation



Alternatives

- * Slow
- * Inaccurate

Our Solution



Our Solution

$$C \frac{dq(t)}{dt} + G (q(t) - q_{\text{amb}}) = p(t)$$

$$s_{i+1} = E s_i + F p_i$$

$$s_{\text{start}} = s_{\text{end}}$$

Our Solution

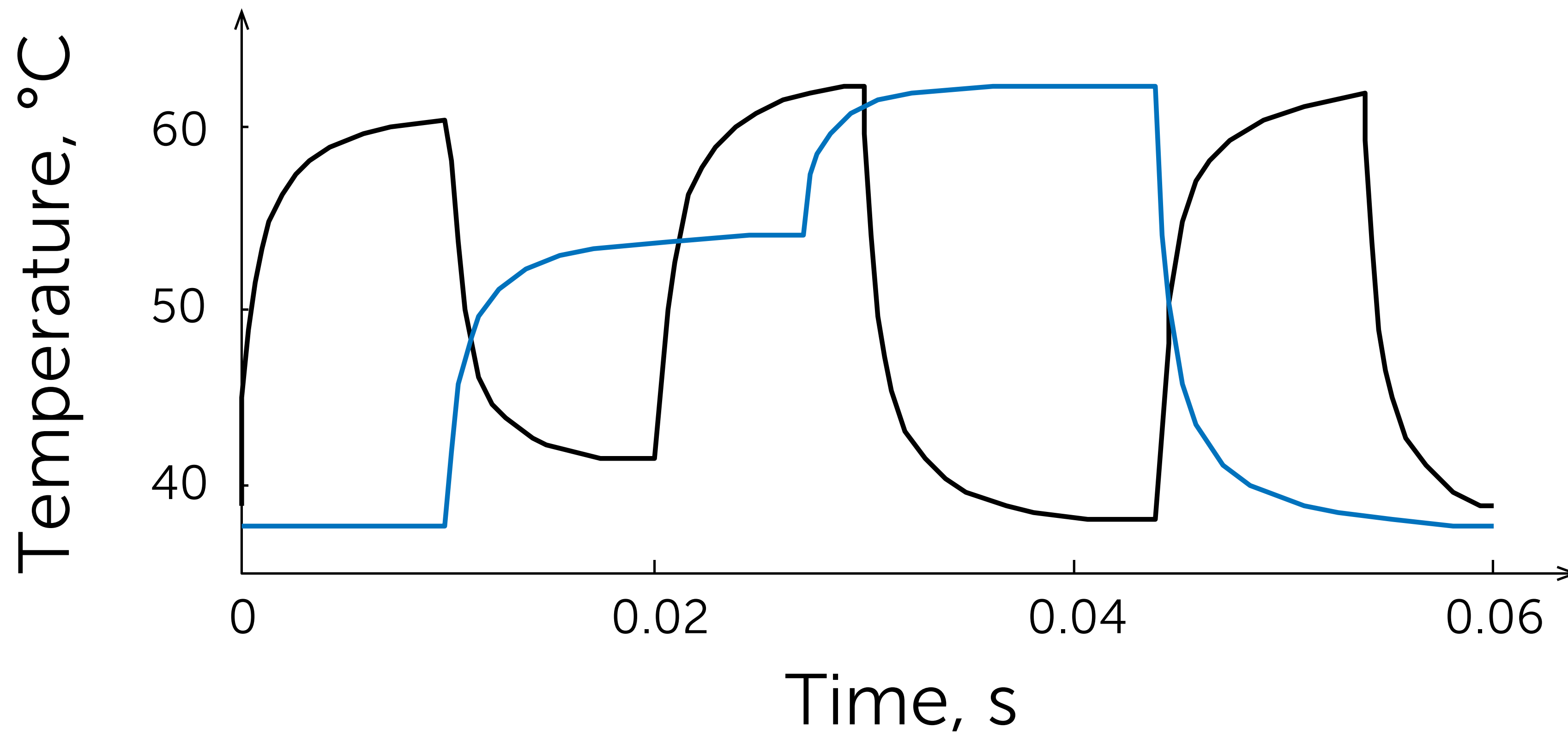
$$AX = B$$

Our Solution

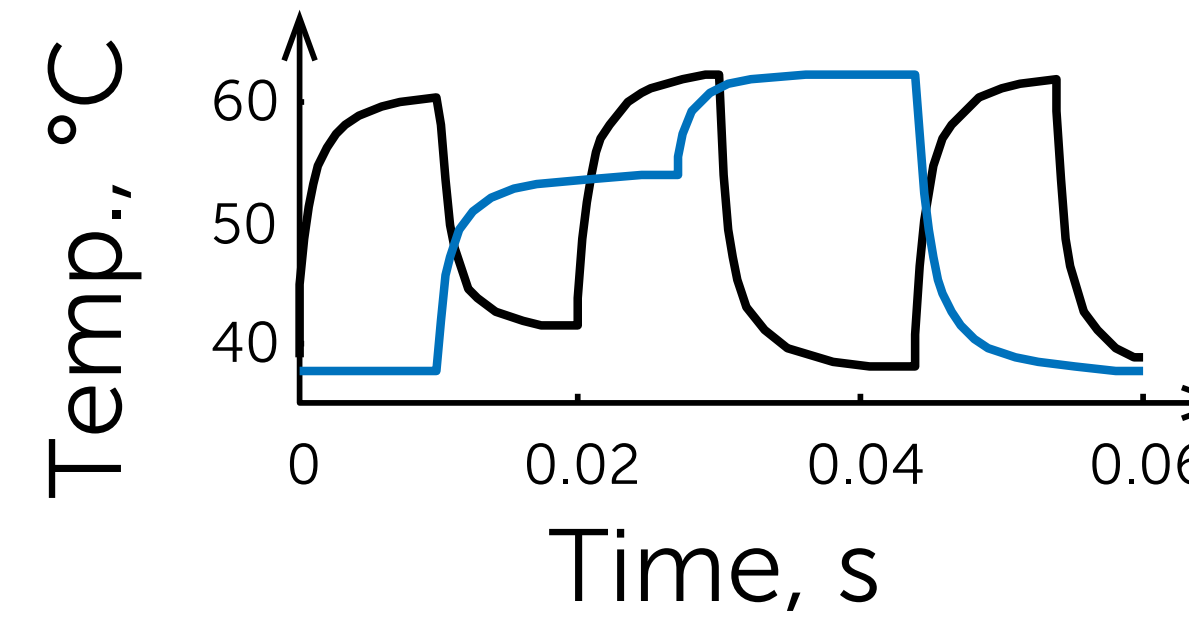
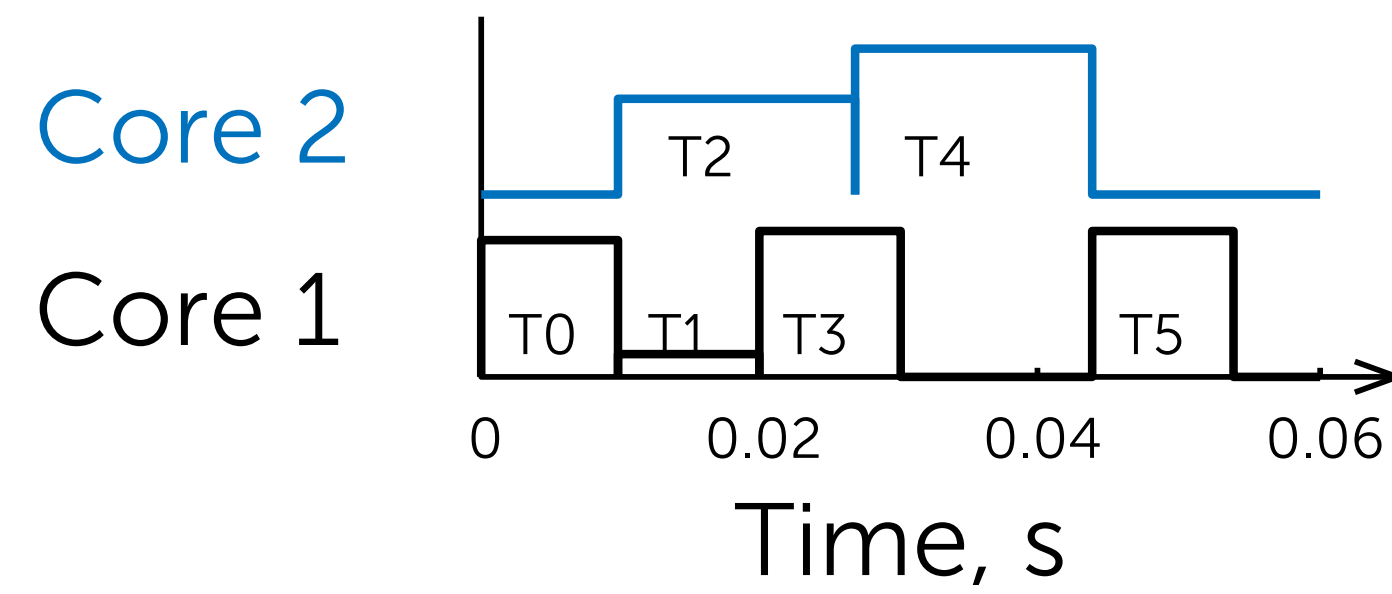
- * Analytical
- * Exact
- * Fast

Reliability Optimization

* Thermal-cyclic fatigue

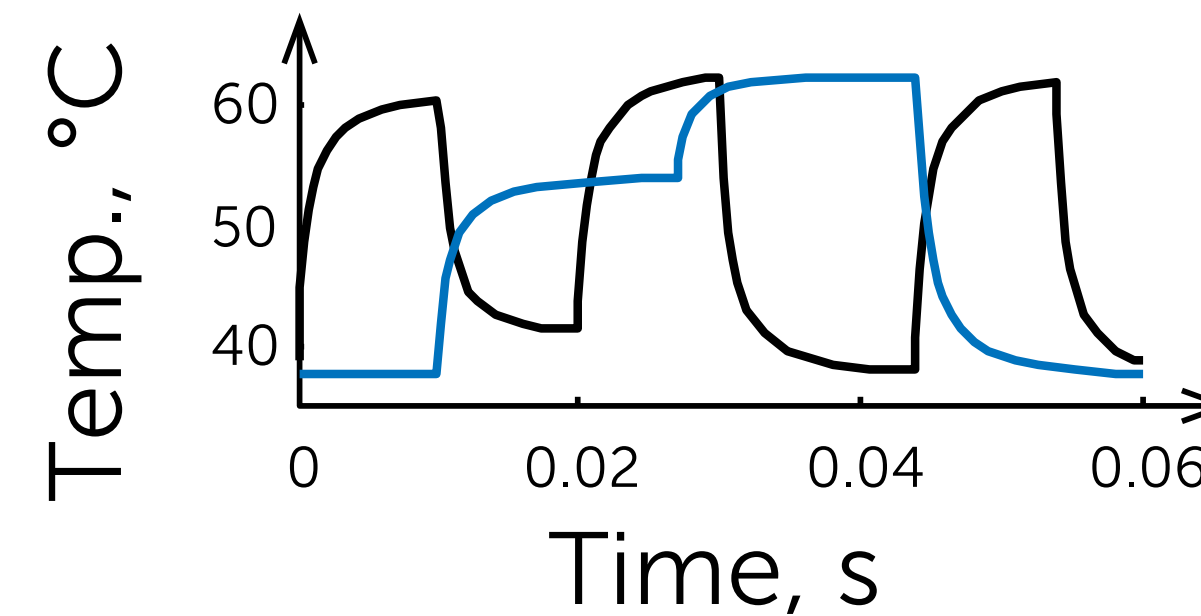
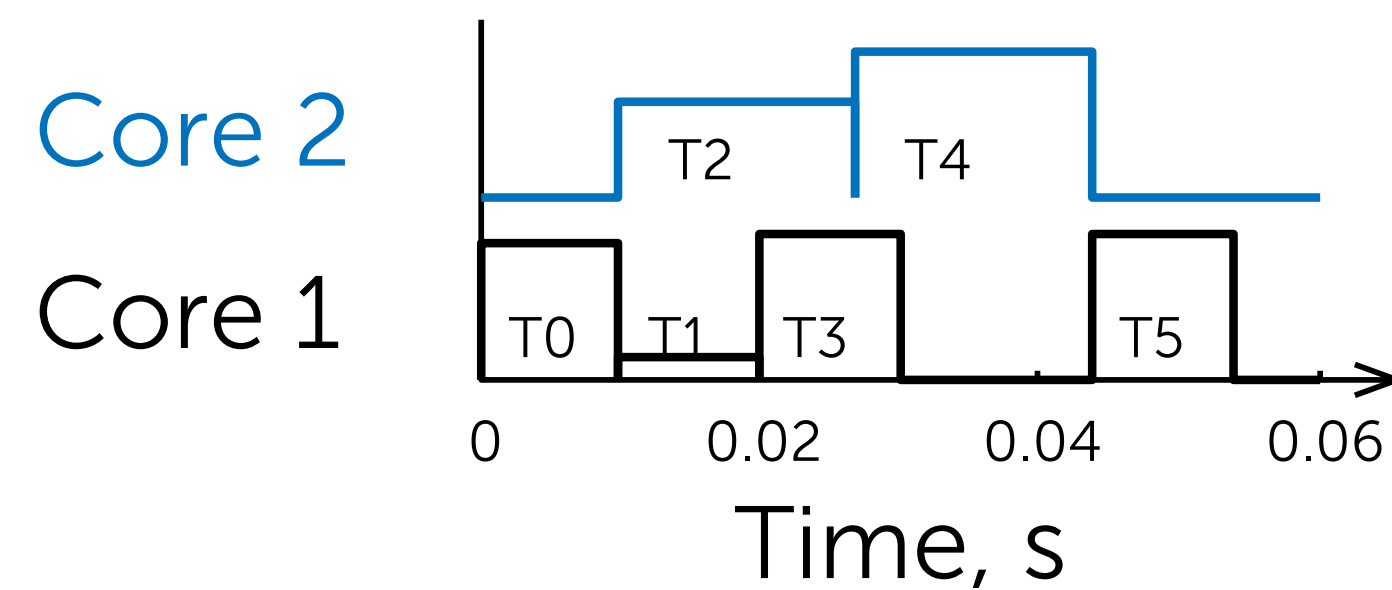


Reliability Optimization

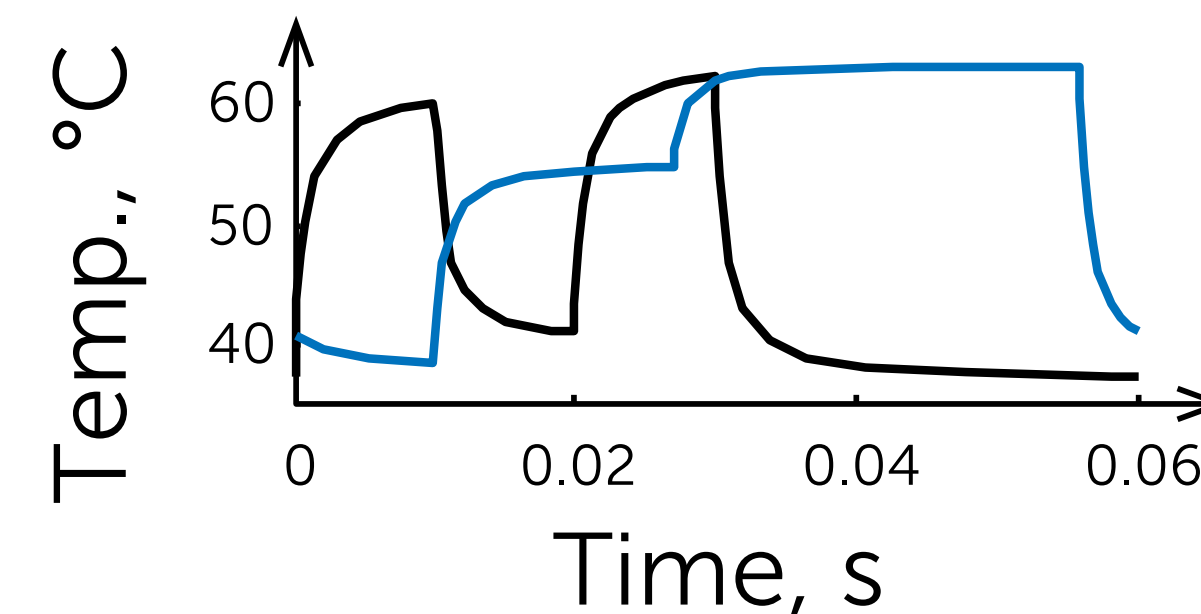
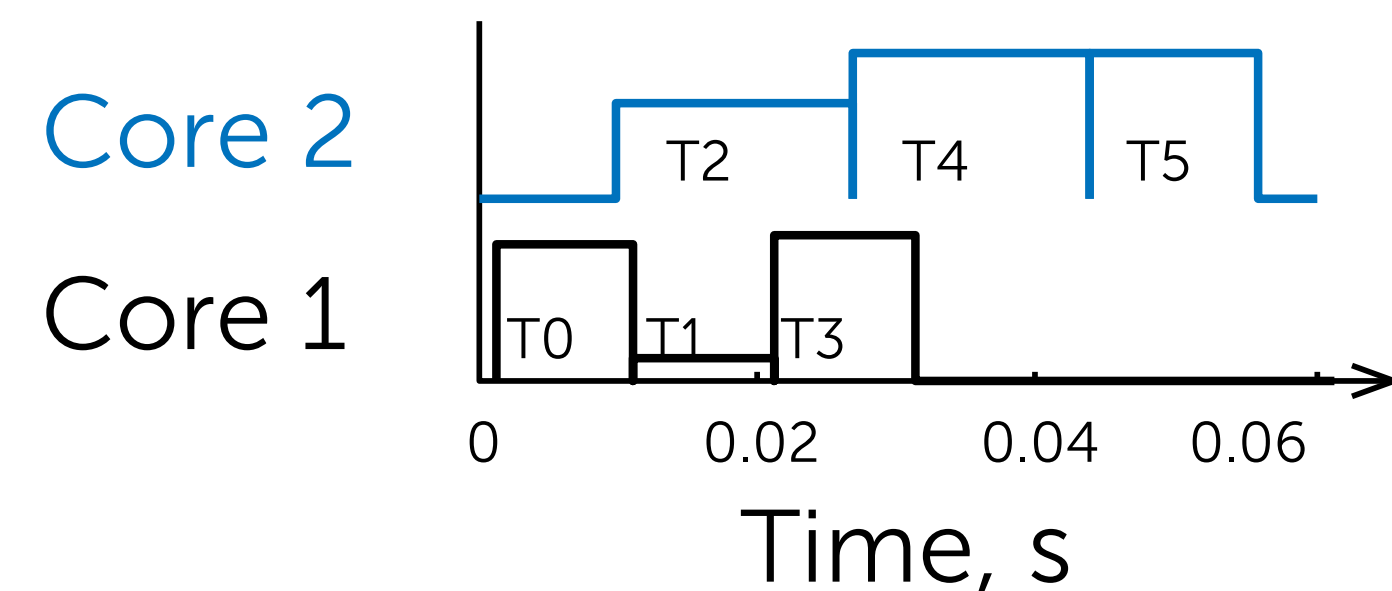


3 cycles

Reliability Optimization

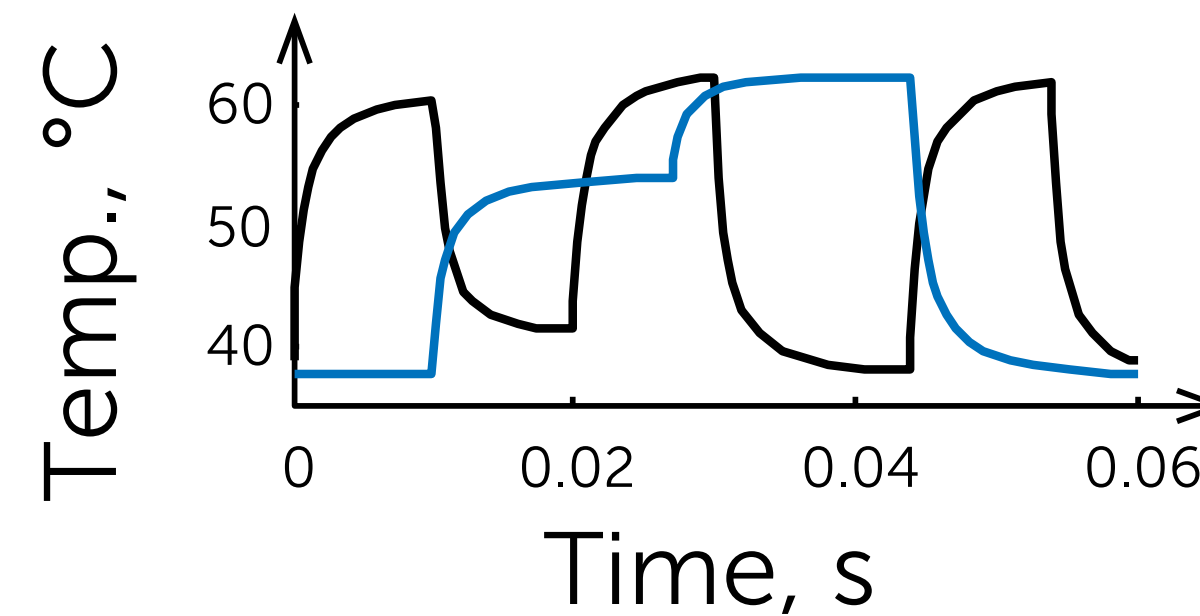
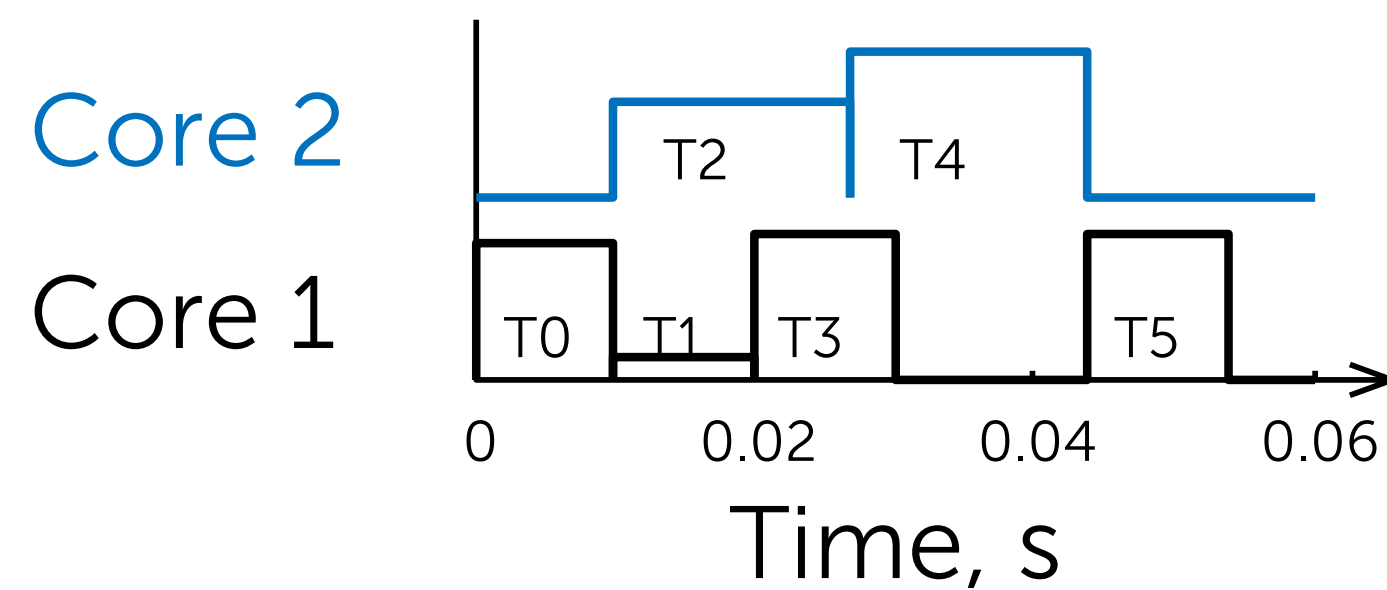


3 cycles

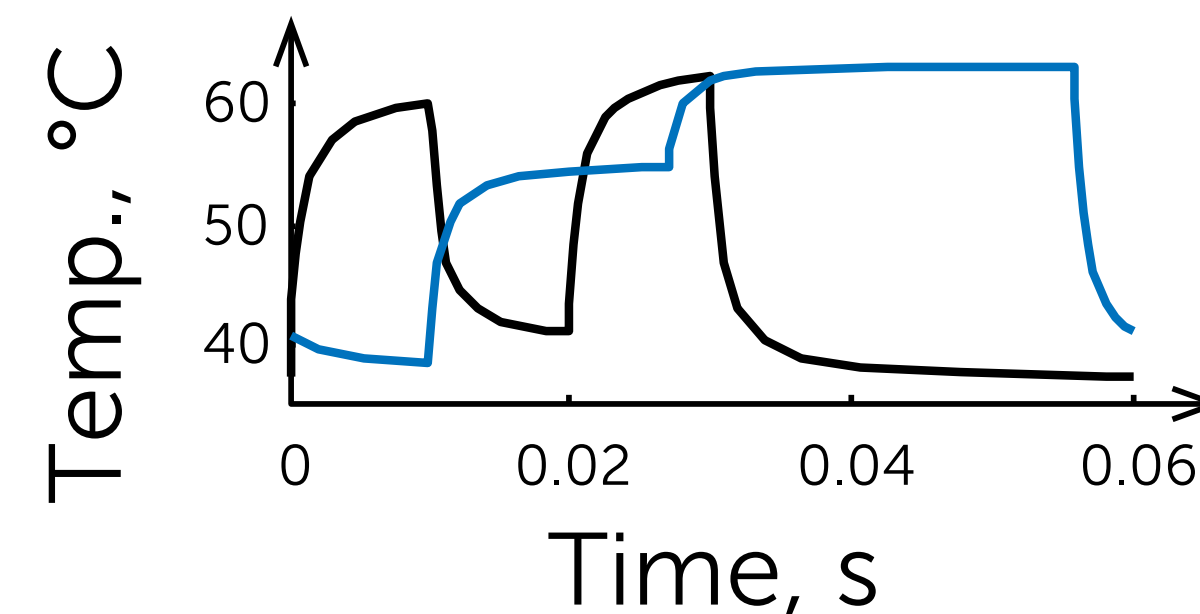
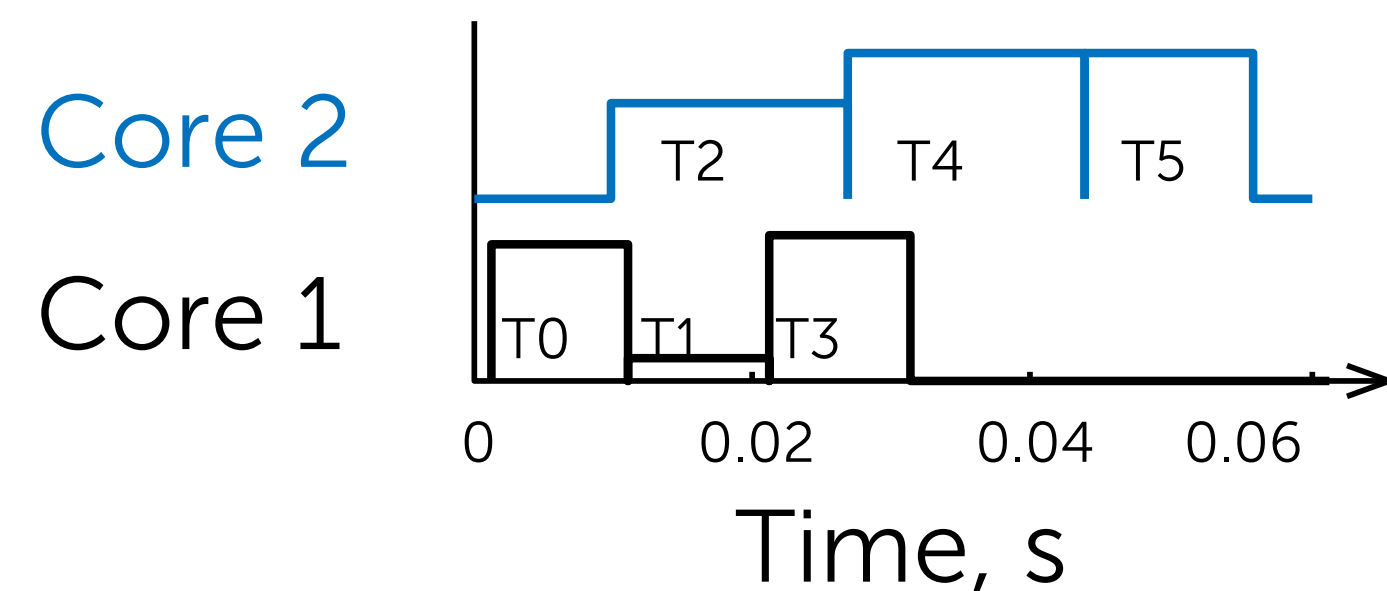


2 cycles,
+45% lifetime

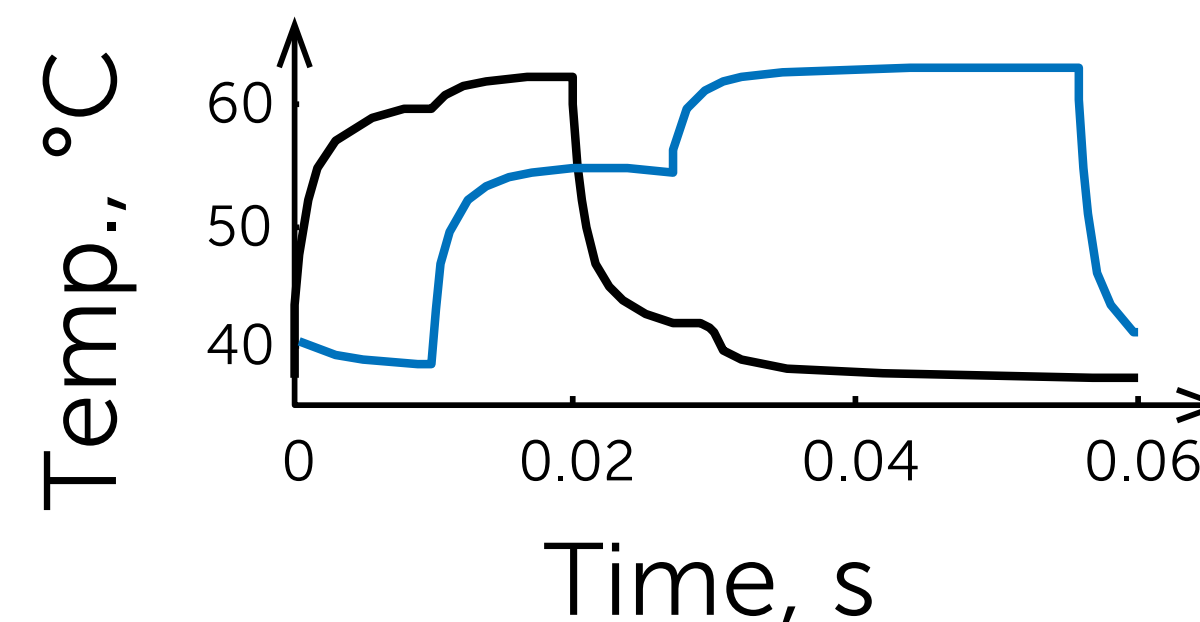
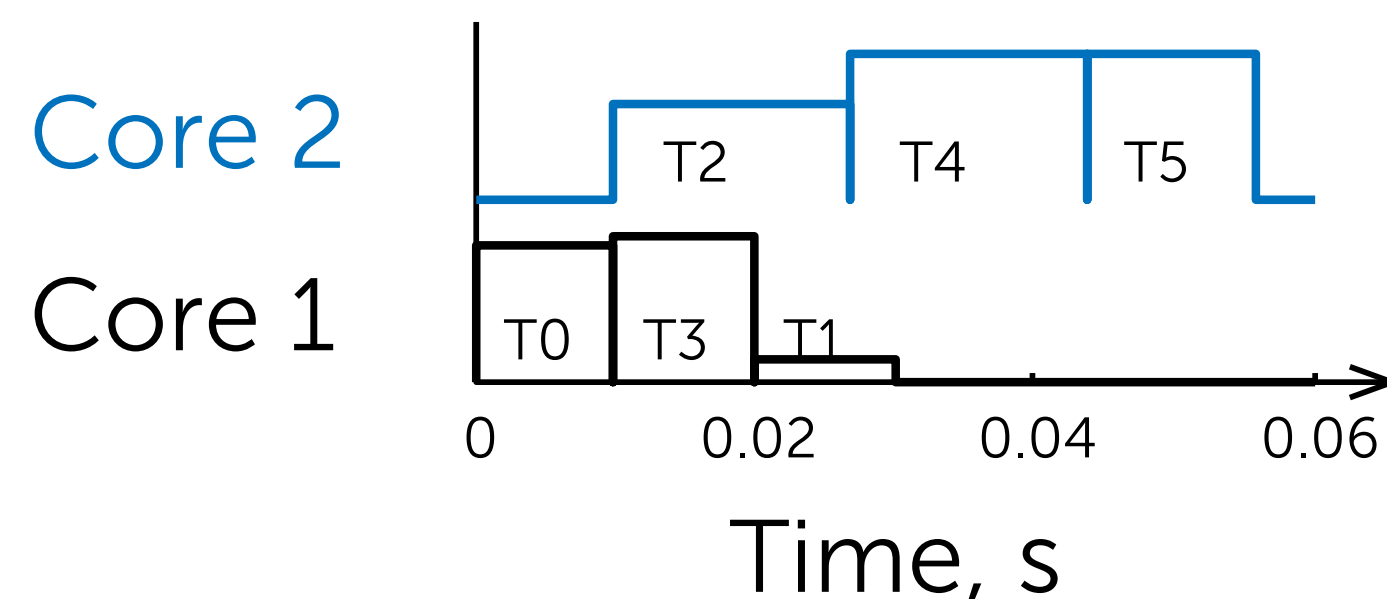
Reliability Optimization



3 cycles



2 cycles,
+45% lifetime



1 cycle,
+55% lifetime

Our Goal

Given:

- * Multiprocessor system
- * Periodic application

Find:

- * Schedule

Such that:

- * Lifetime maximized
- * Energy minimized

Our Solution

- * Dynamic steady-state temperature analysis
- * Genetic algorithm with multiple objectives

Outline



Dynamic Steady-State Temperature Analysis
and Reliability Optimization



**Statistical Analysis of Process Variation
Based on Indirect Measurements**

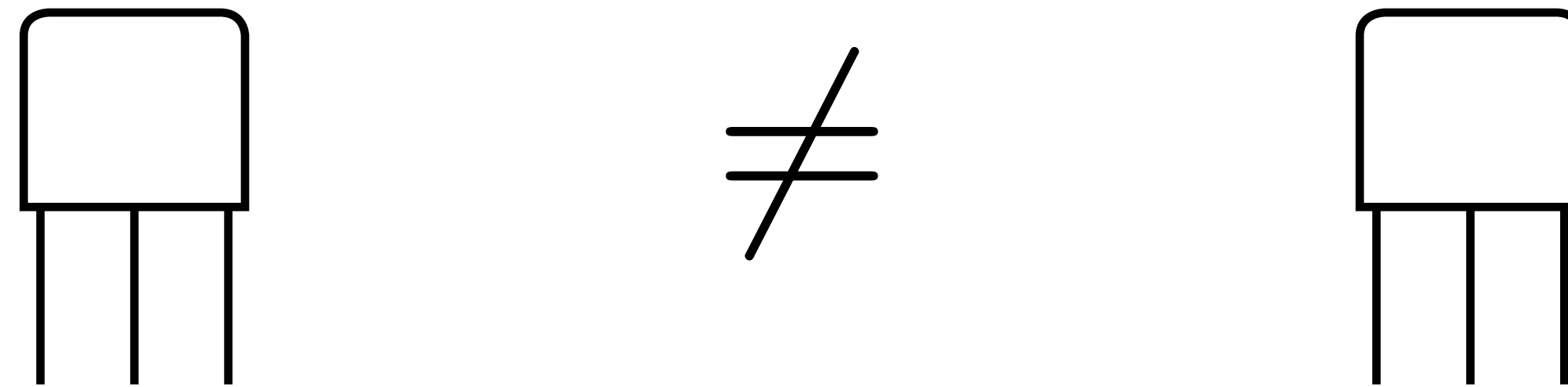


Probabilistic Analysis of Power and
Temperature Under Process Variation

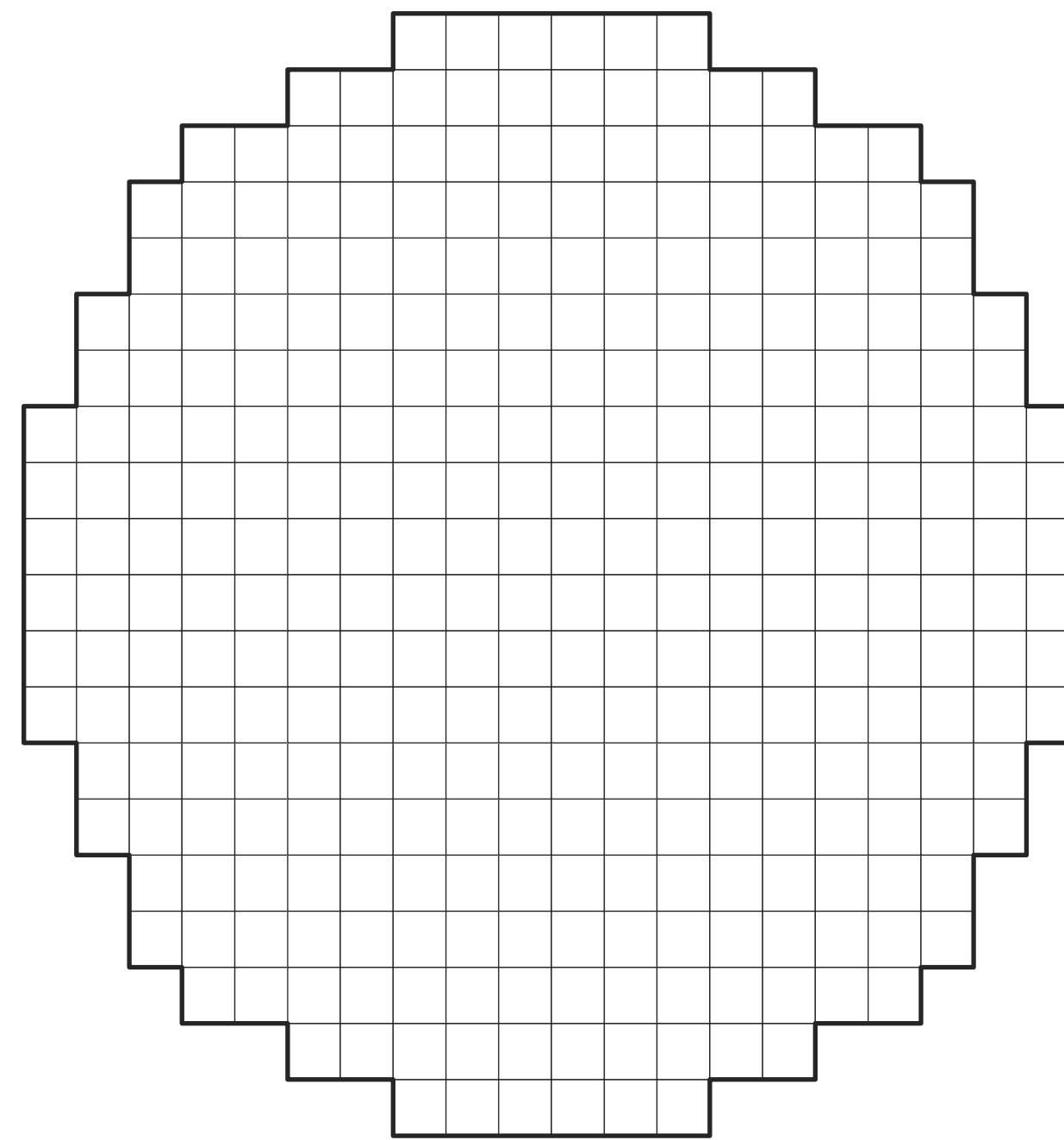


Temperature-Centric Reliability Analysis
and Optimization Under Process Variation

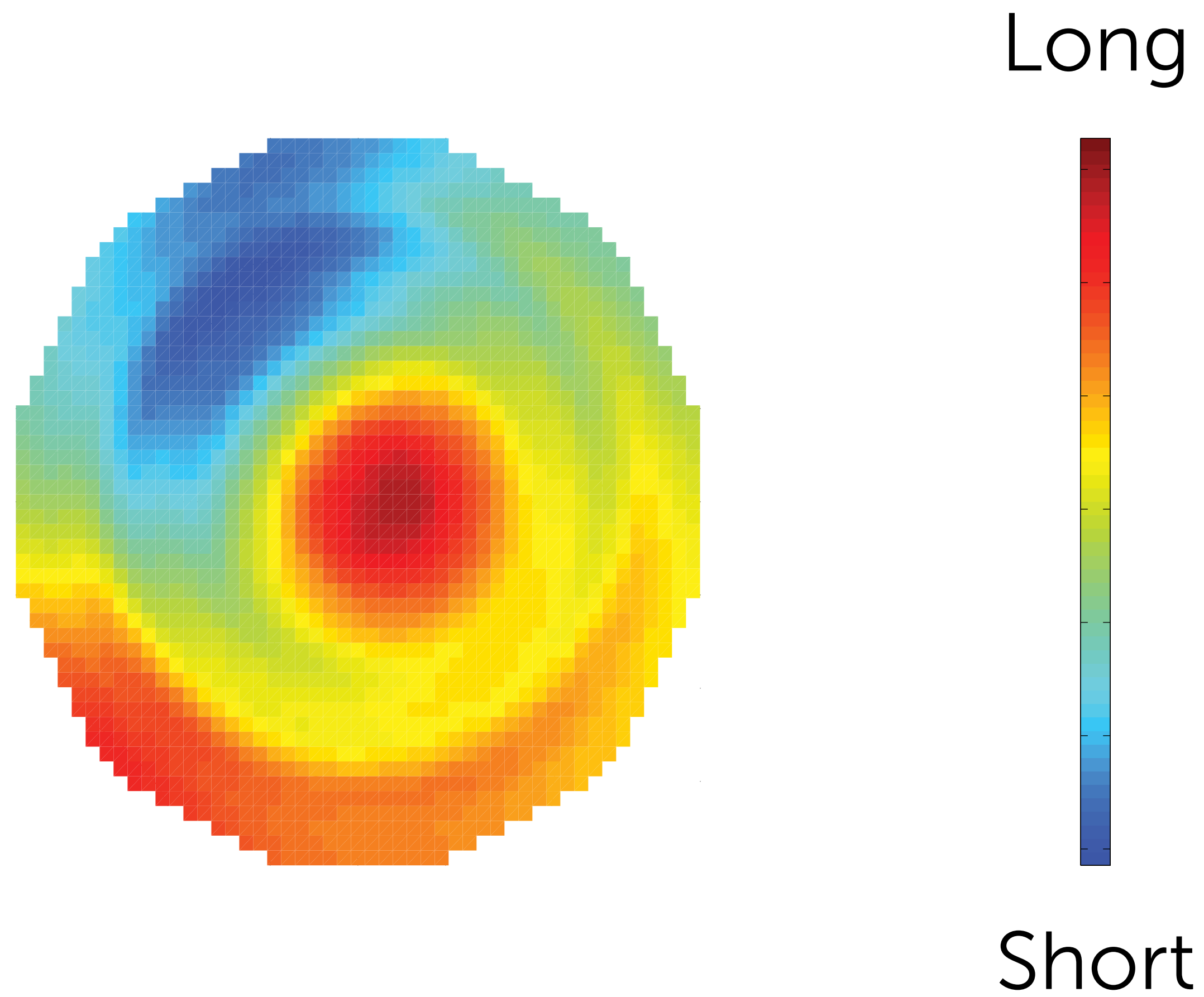
Process Variation



Process Variation

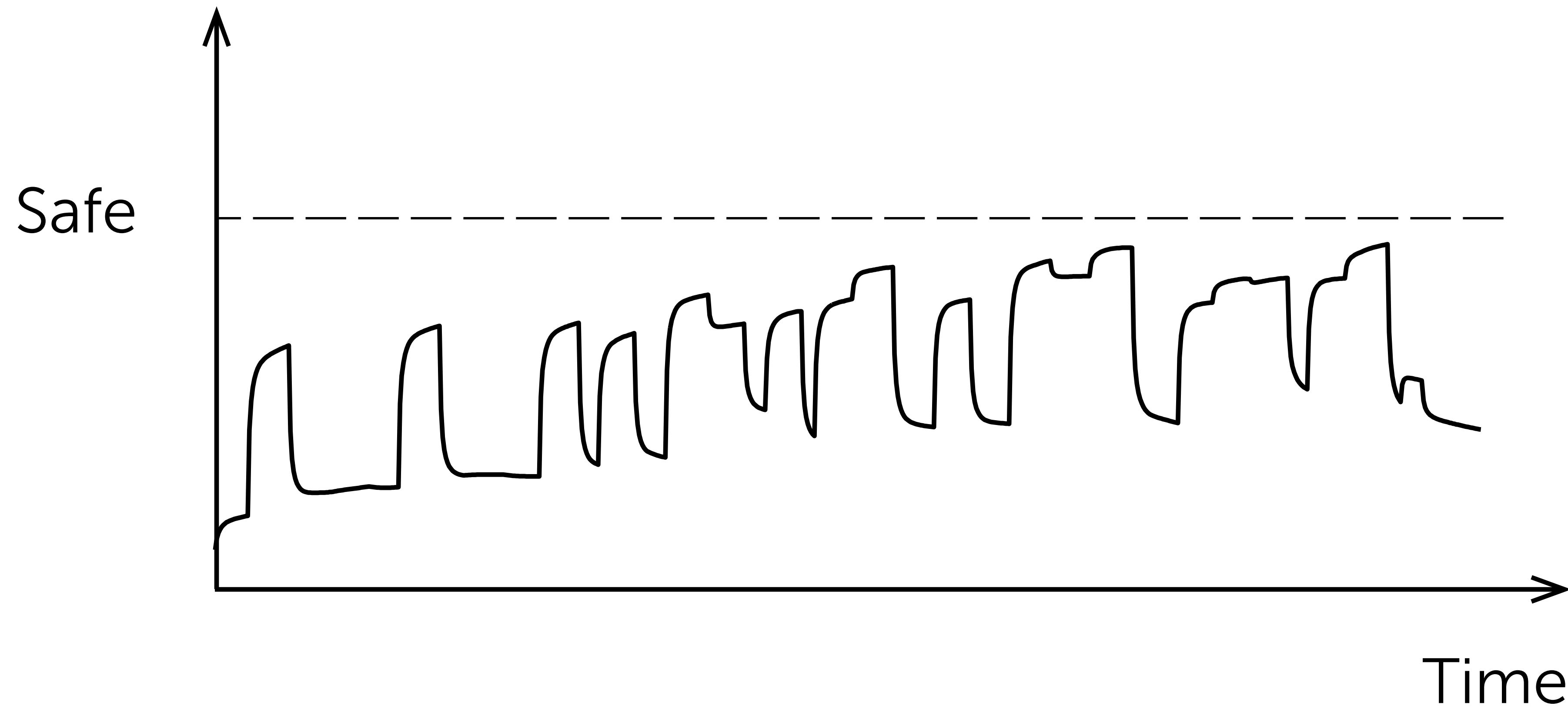


Process Variation



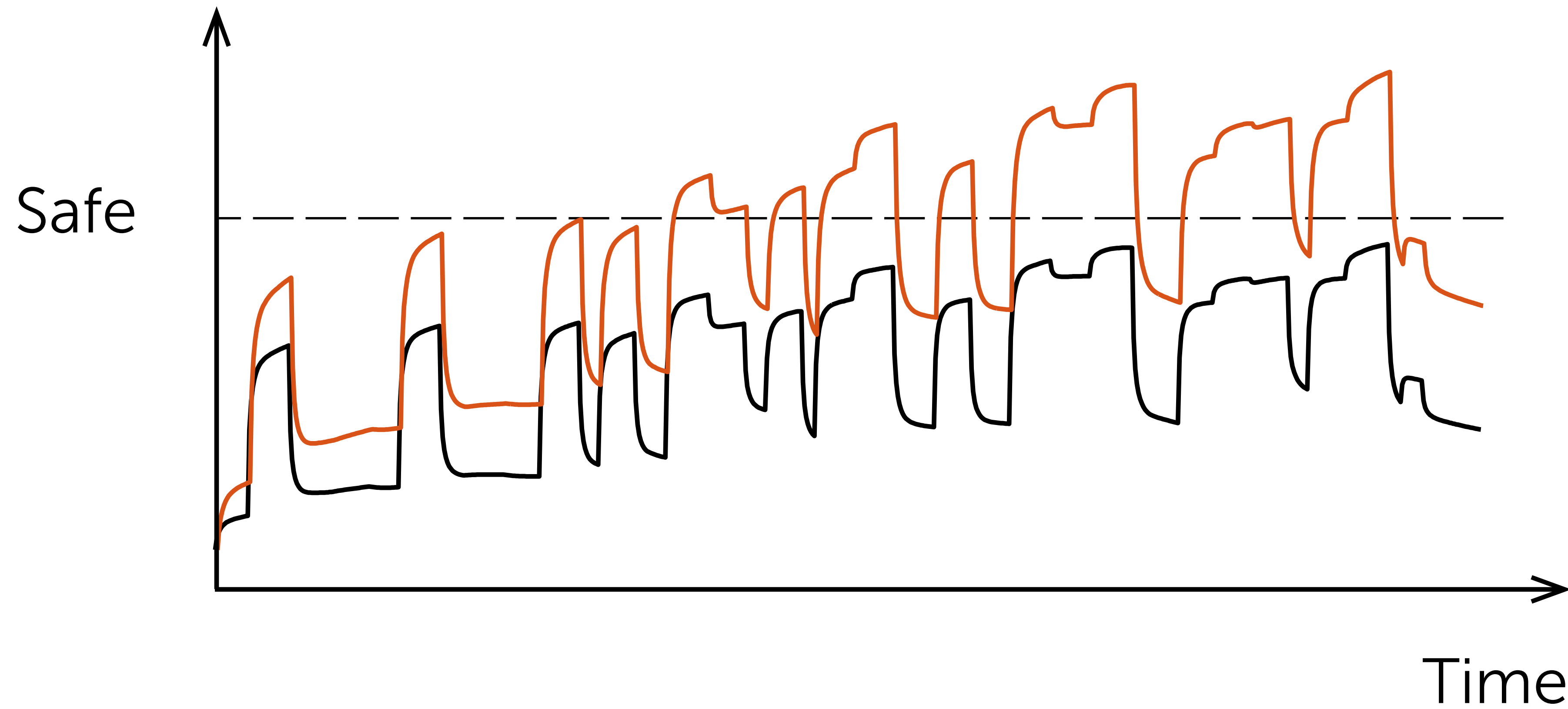
Process Variation

Temperature

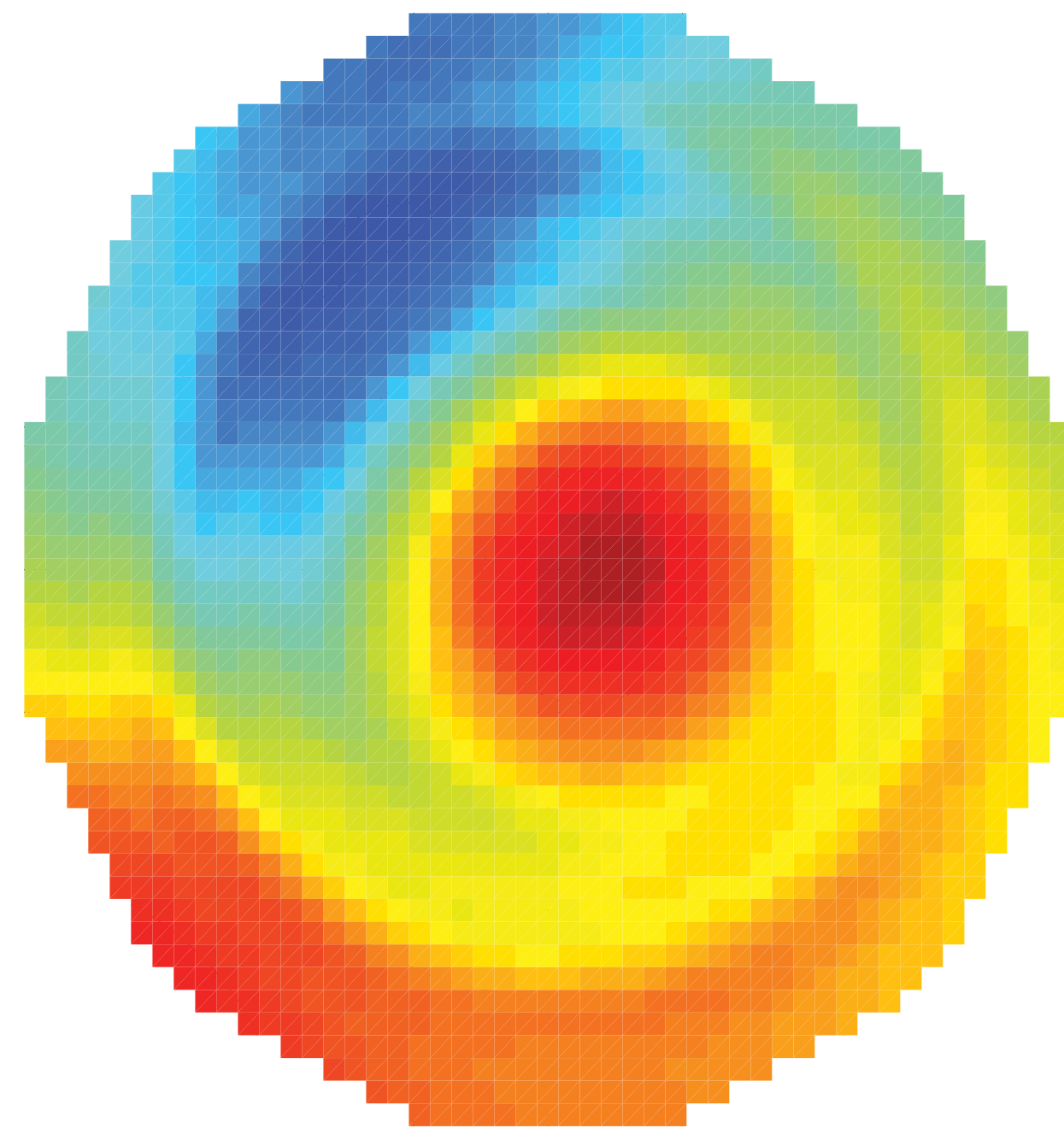


Process Variation

Temperature



Our Goal

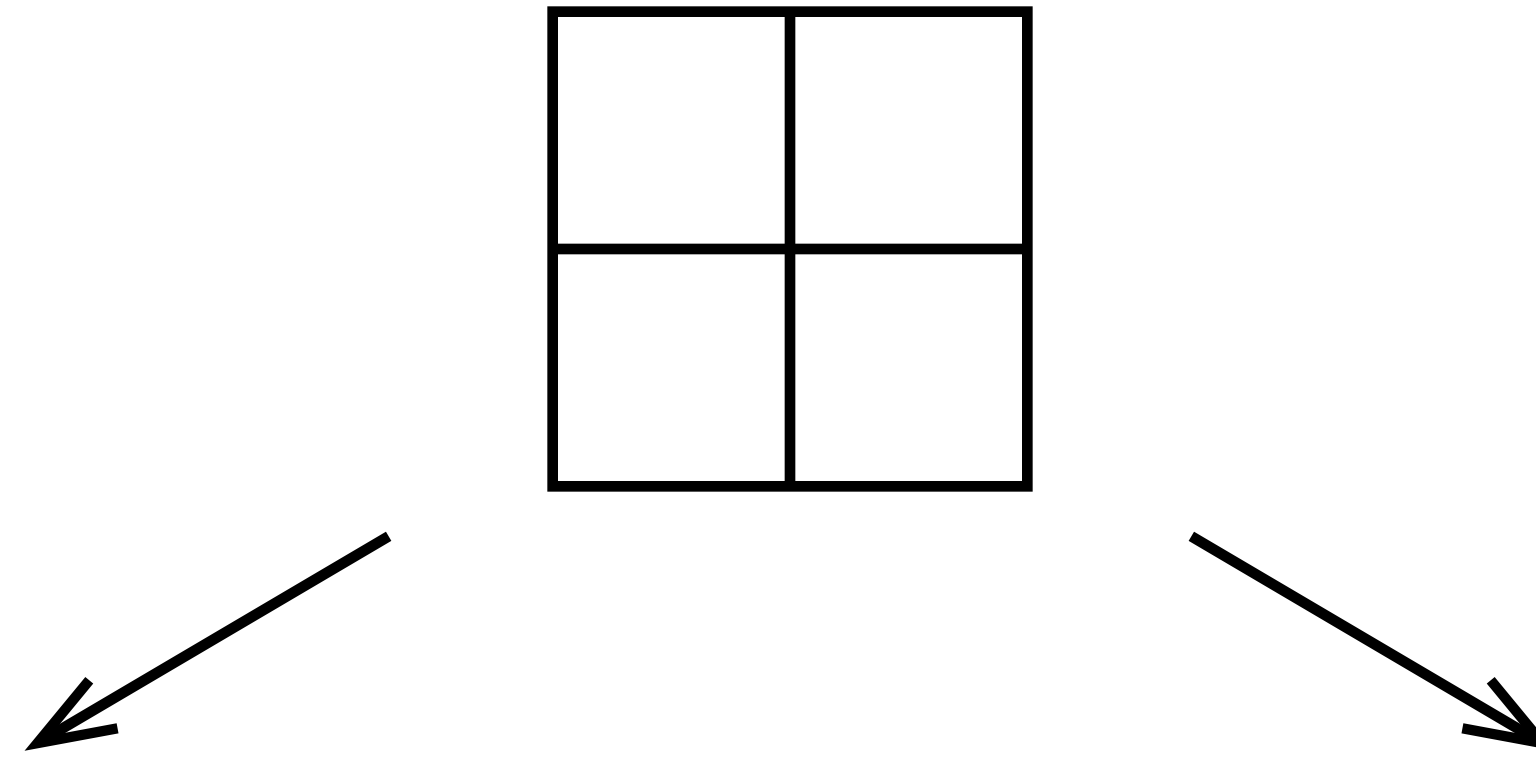


Our Goal

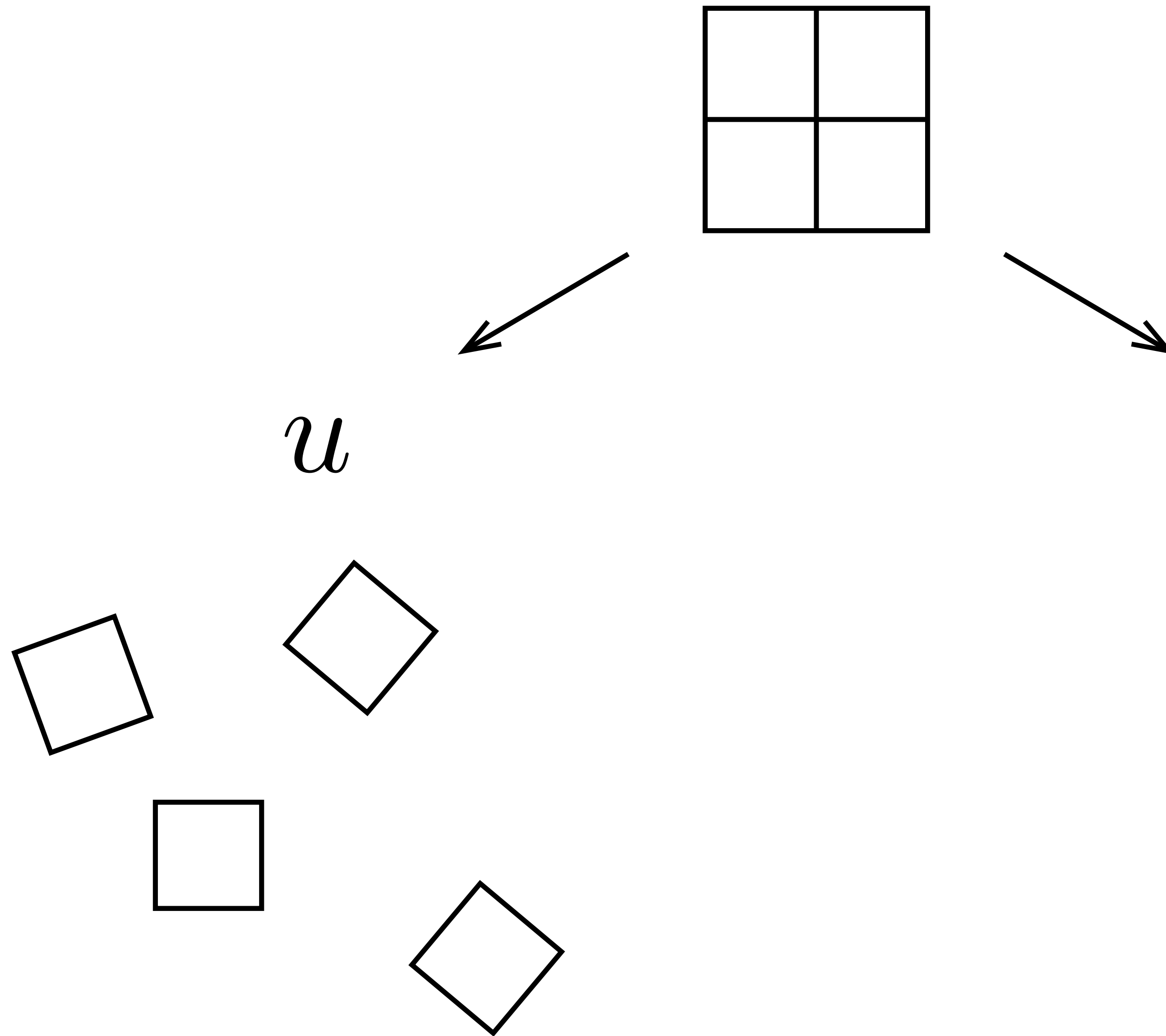


Quantity of interest

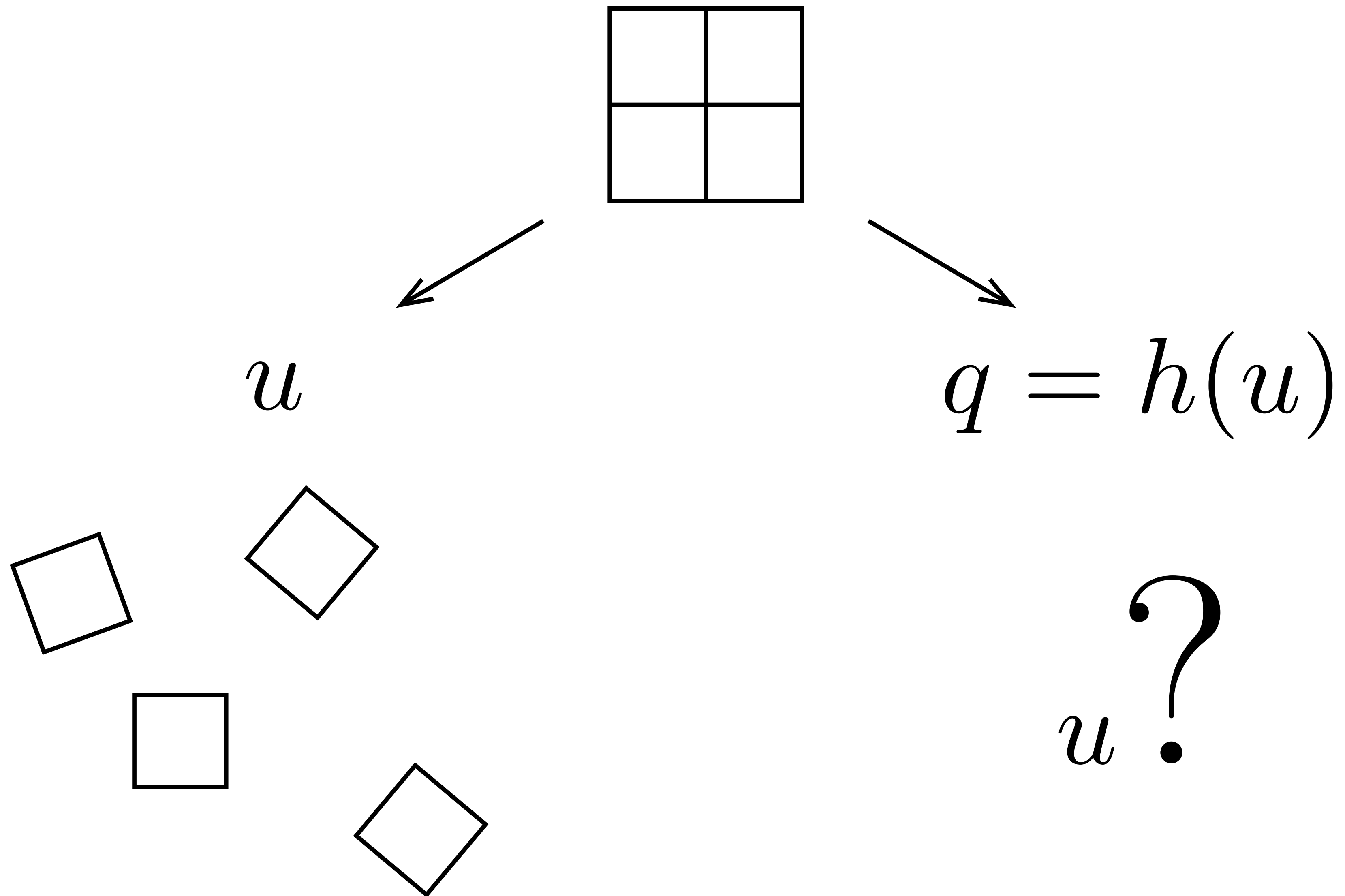
Alternatives



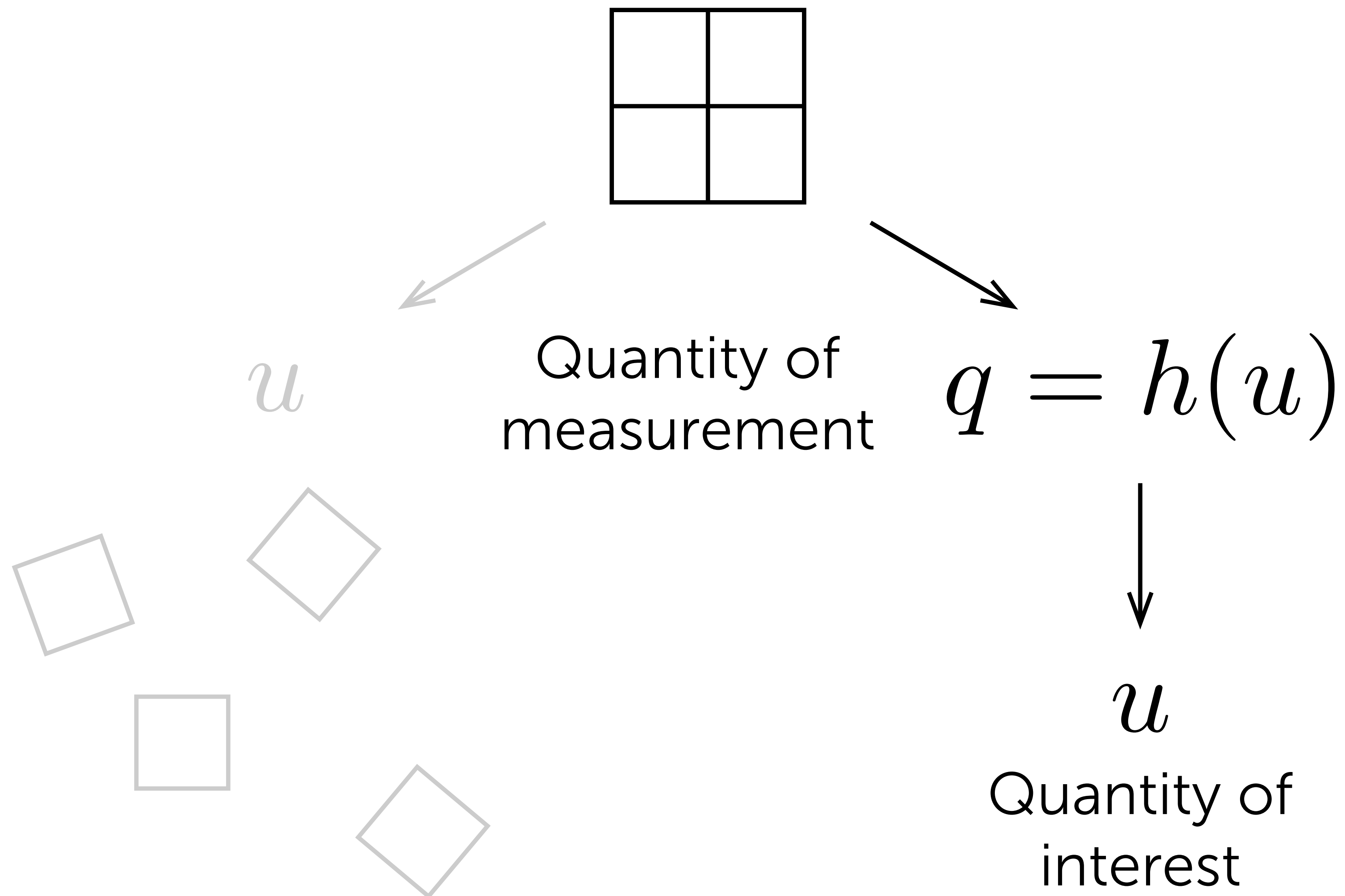
Alternatives



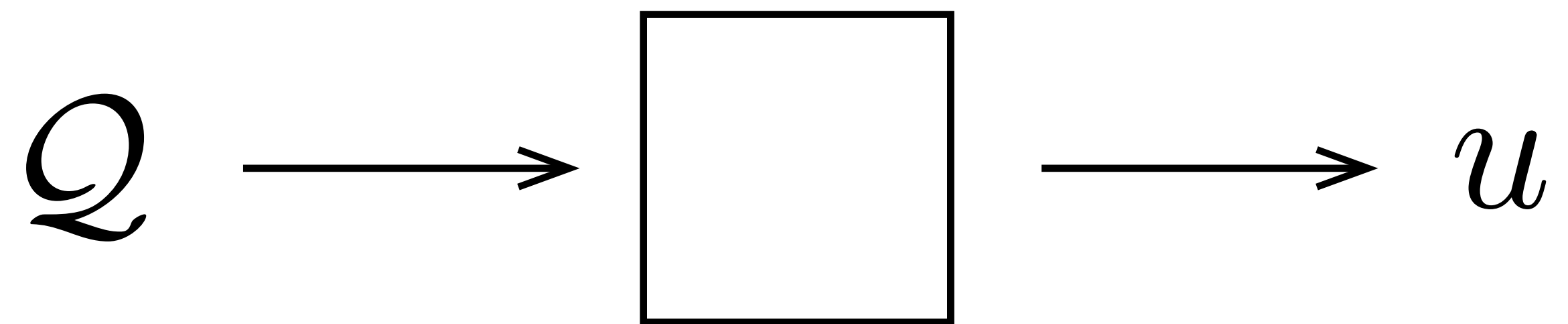
Alternatives



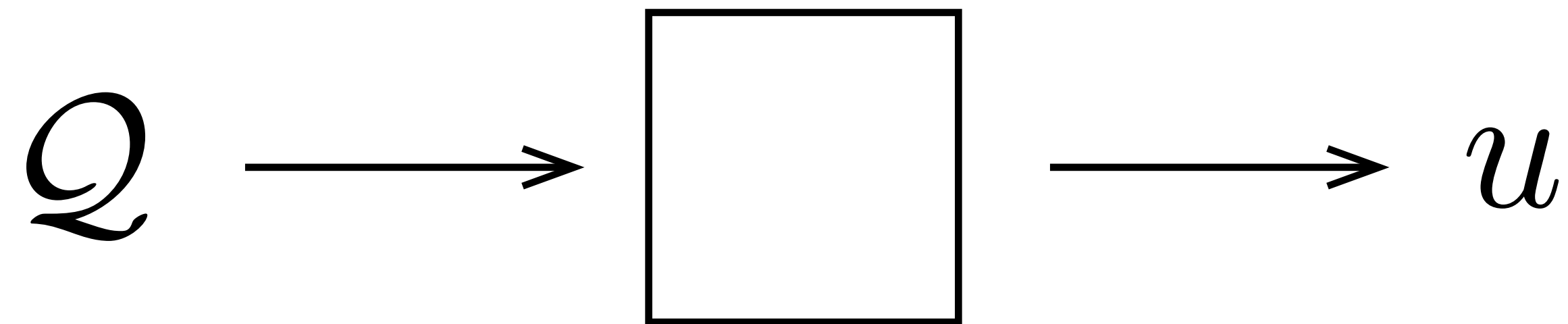
Our Solution



Our Solution

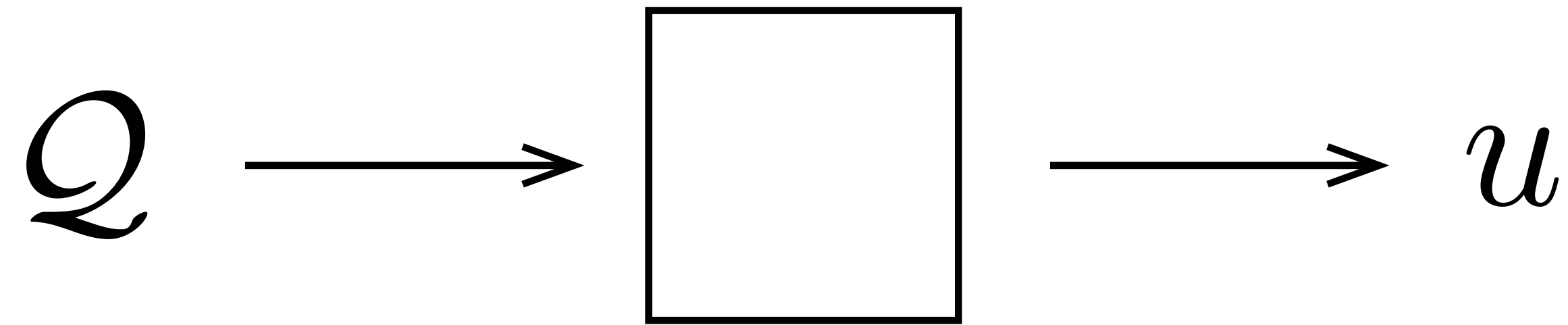


Our Solution



Indirect
Incomplete
Noisy

Our Solution



Indirect
Incomplete
Noisy

Primary
Comprehensive
Efficient

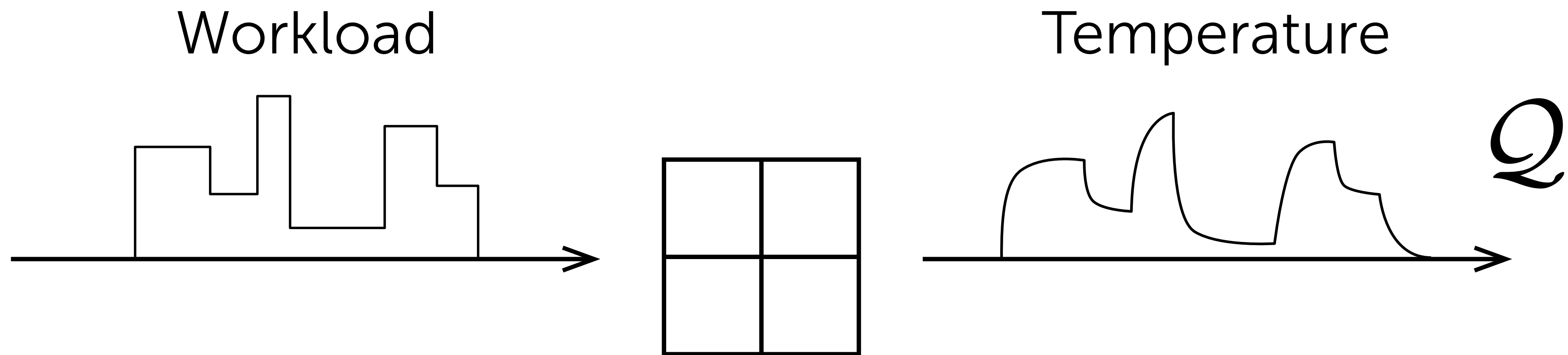
Bayesian Inference

$$p(u|\mathcal{Q}) \propto p(\mathcal{Q}|u) \times p(u)$$

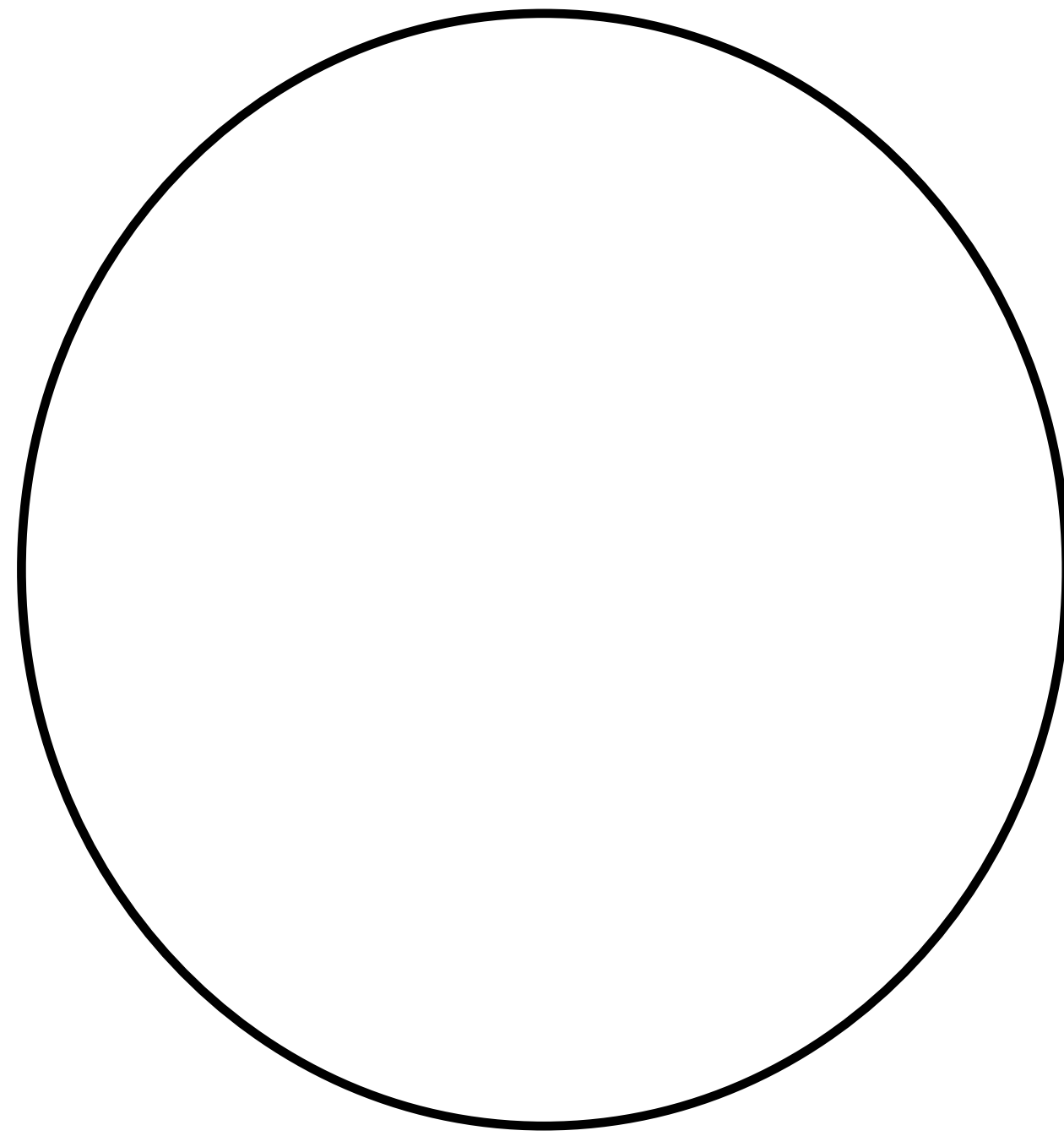
Illustrative Example

u Channel length

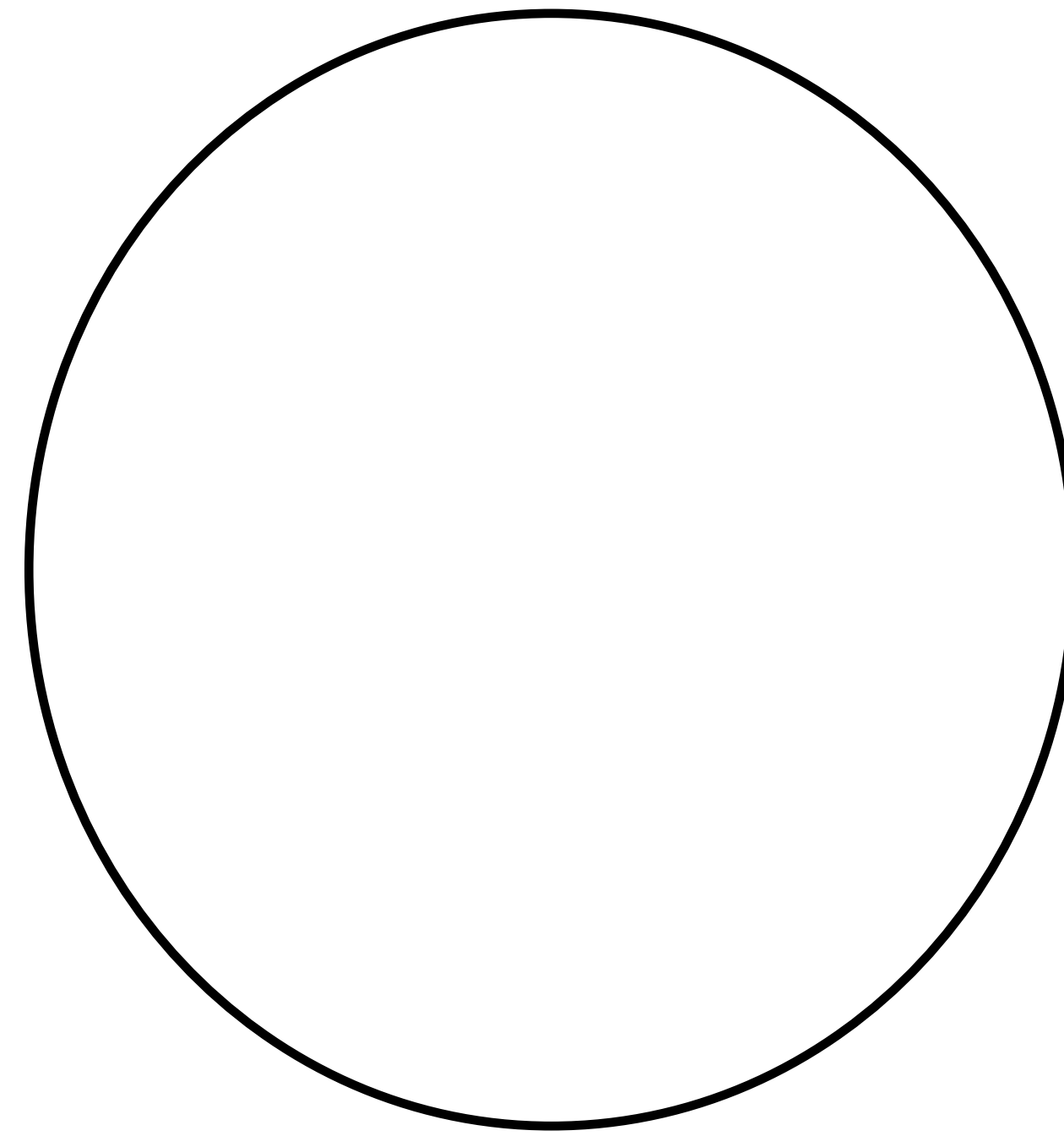
q Temperature



Illustrative Example

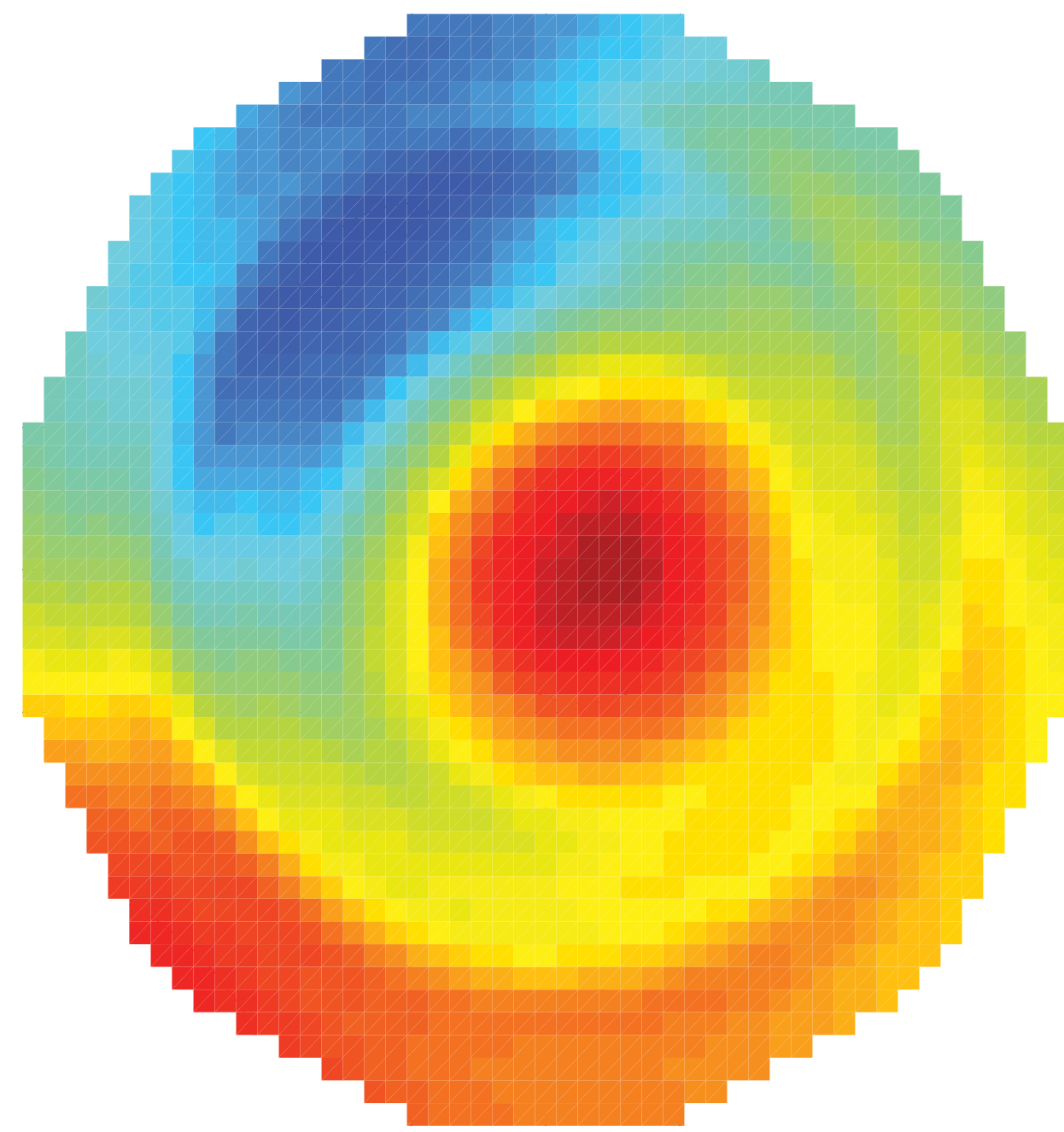


True

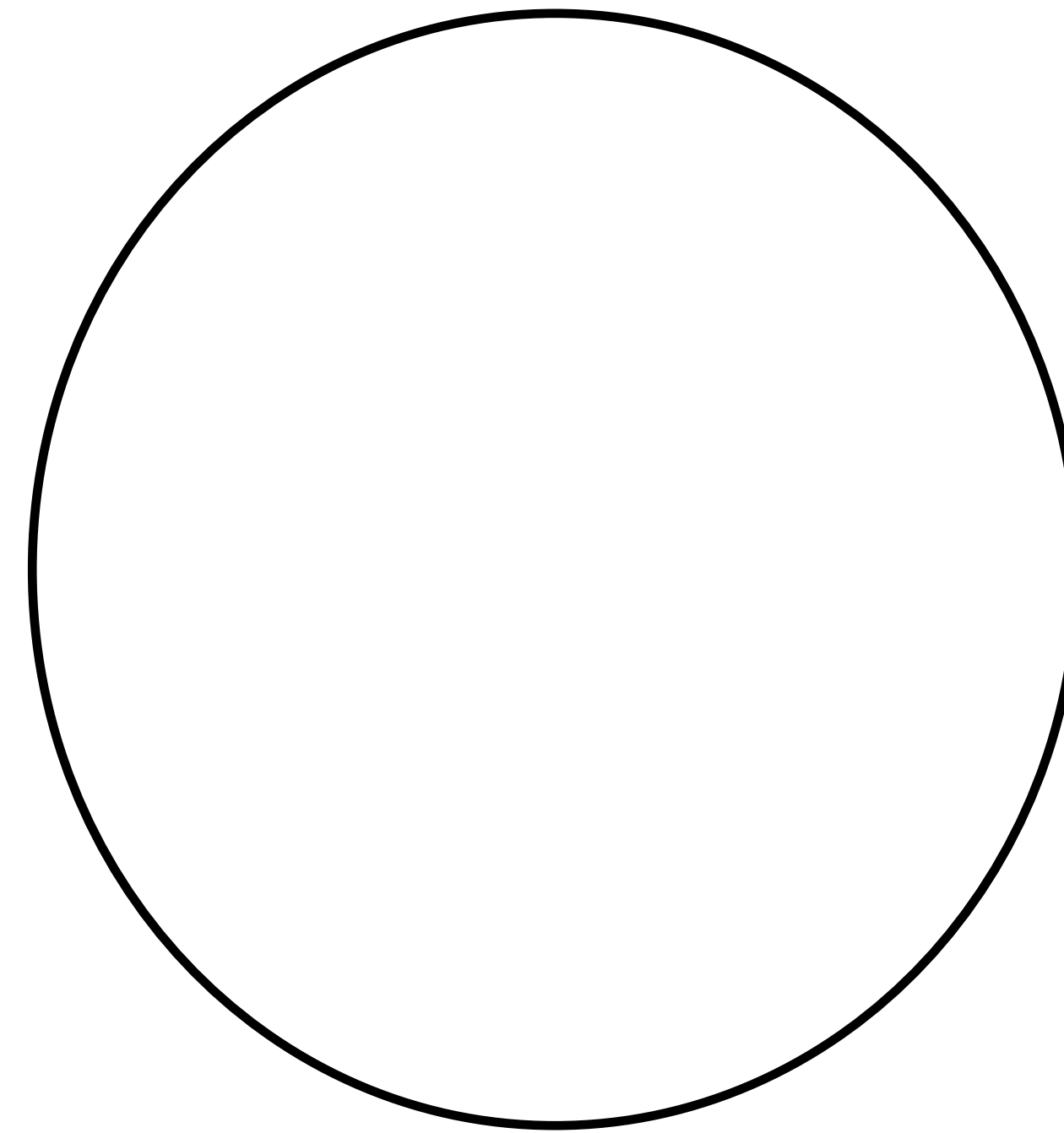


Inferred

Illustrative Example

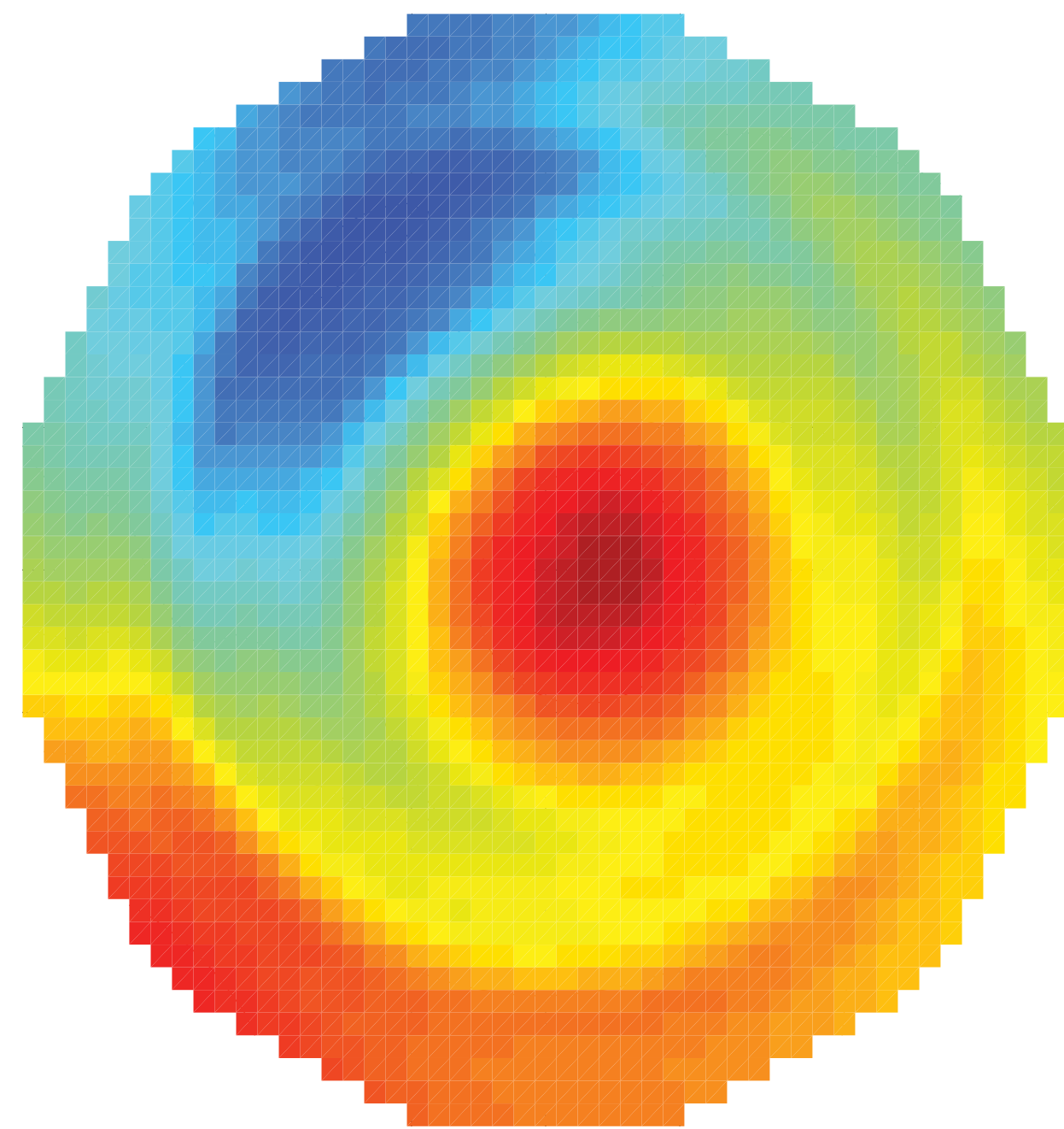


True

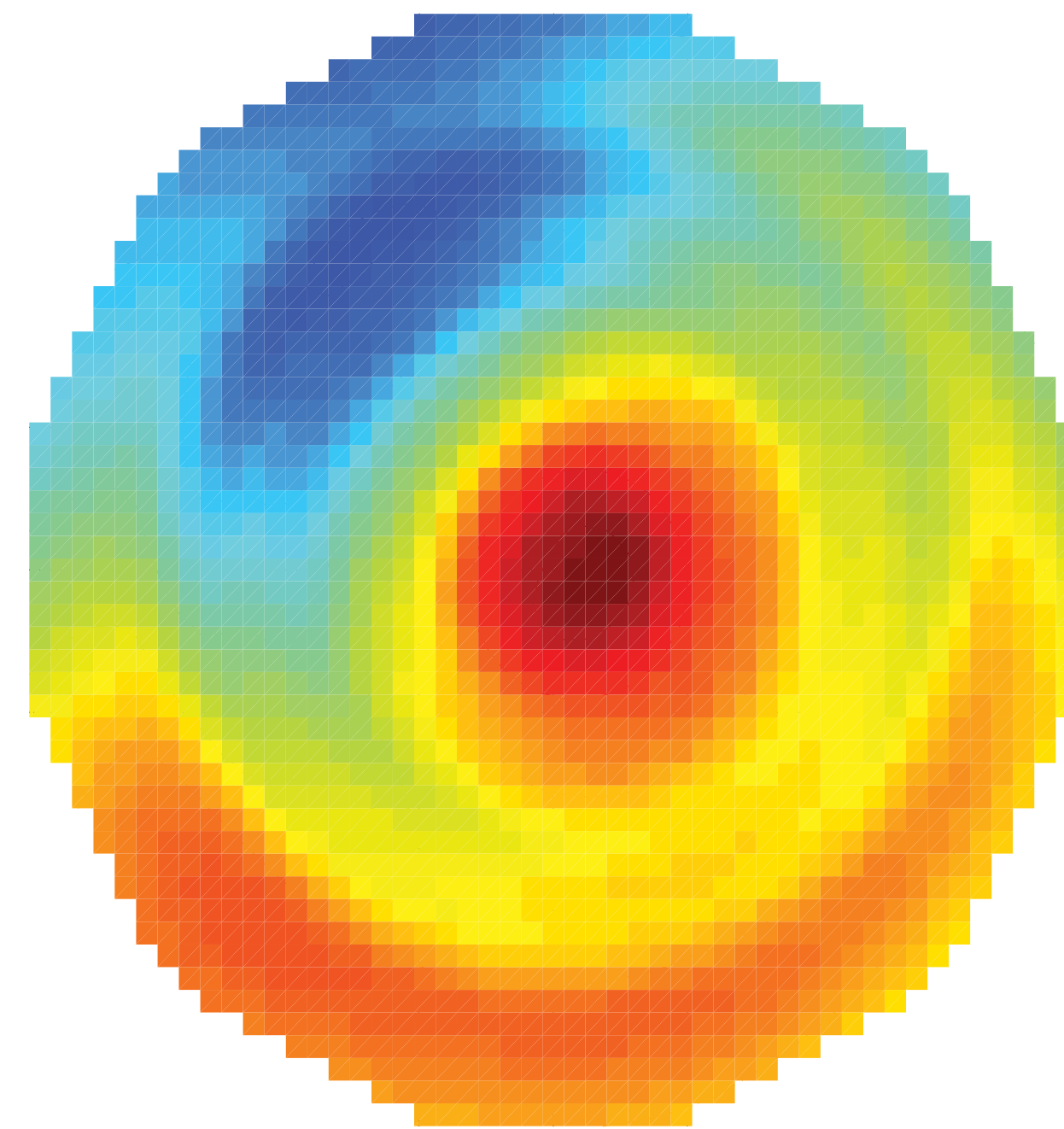


Inferred

Illustrative Example



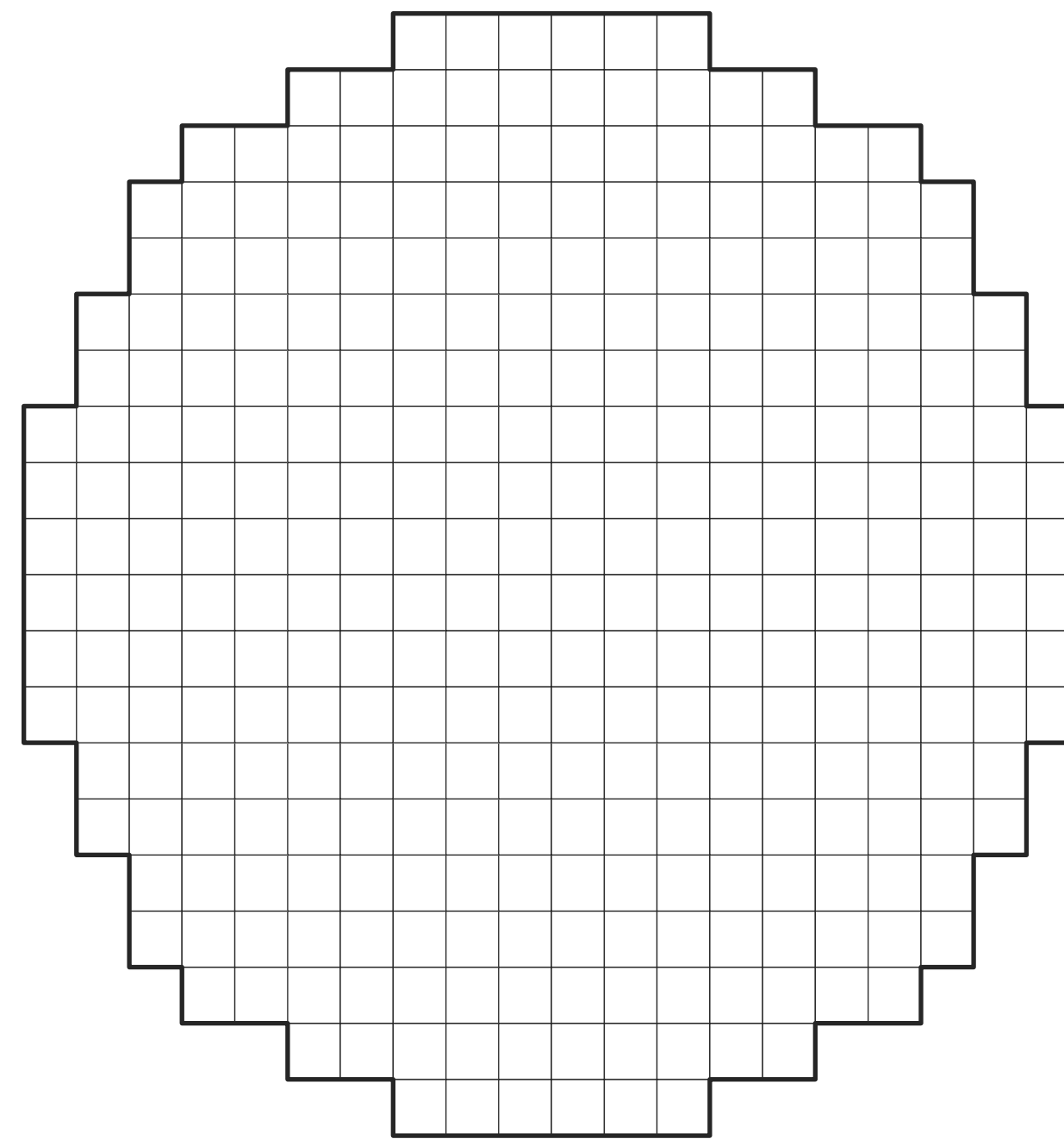
True



Inferred

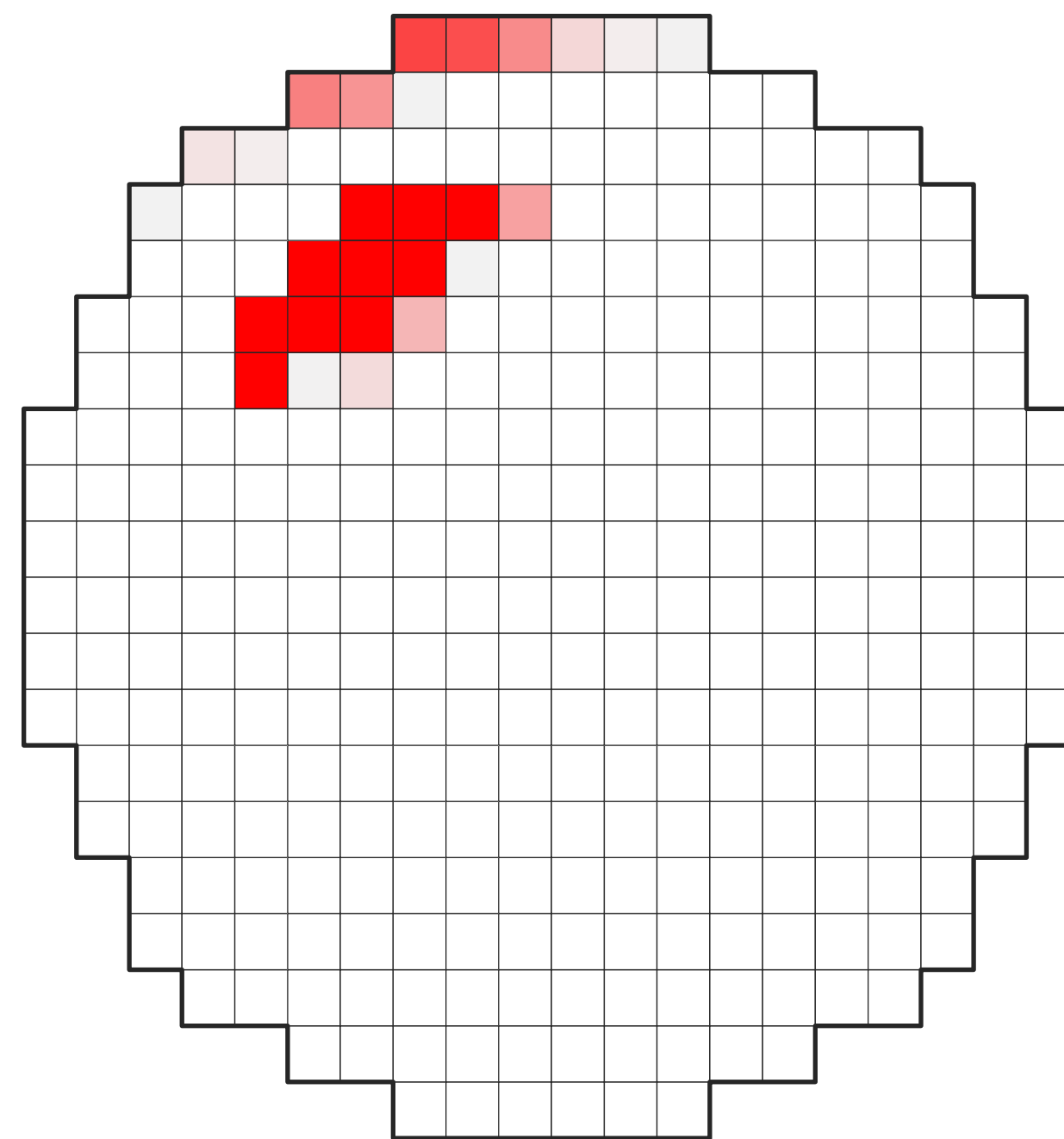
Illustrative Example

$$P(u < u_*)$$



Illustrative Example

$$P(u < u_*)$$



Outline



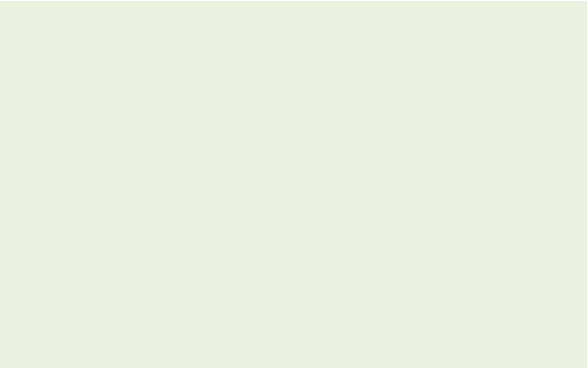
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**Probabilistic Analysis of Power and
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Temperature-Centric Reliability Analysis
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Our Goal

Given:

- * Multiprocessor system
- * Process variation

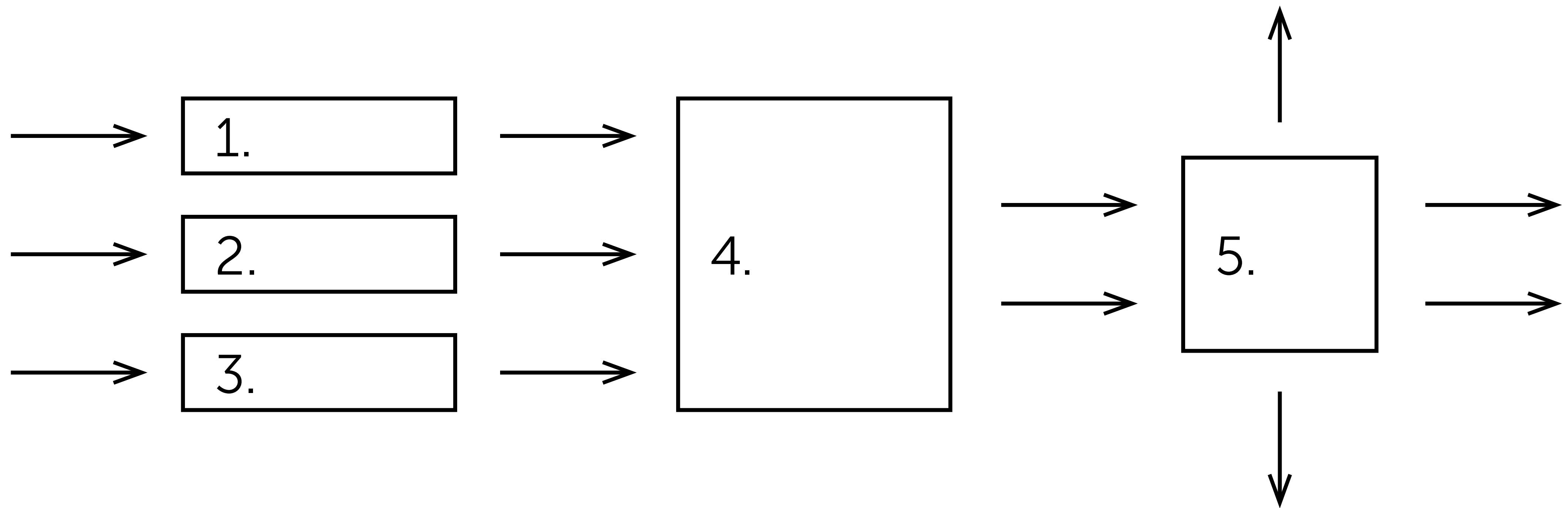
Find:

- * Probability distributions of transient power and temperature profiles

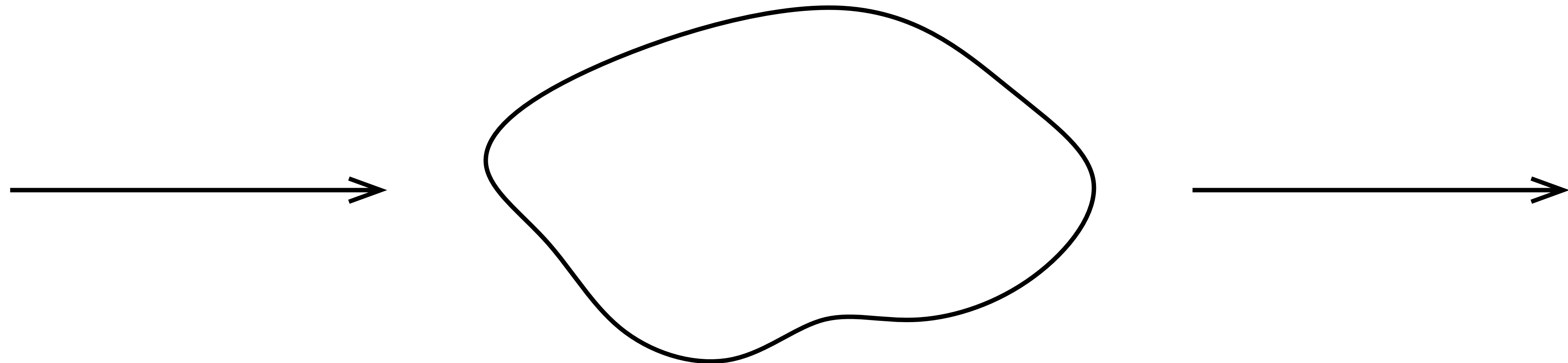
Such that:

- * Accurate and fast

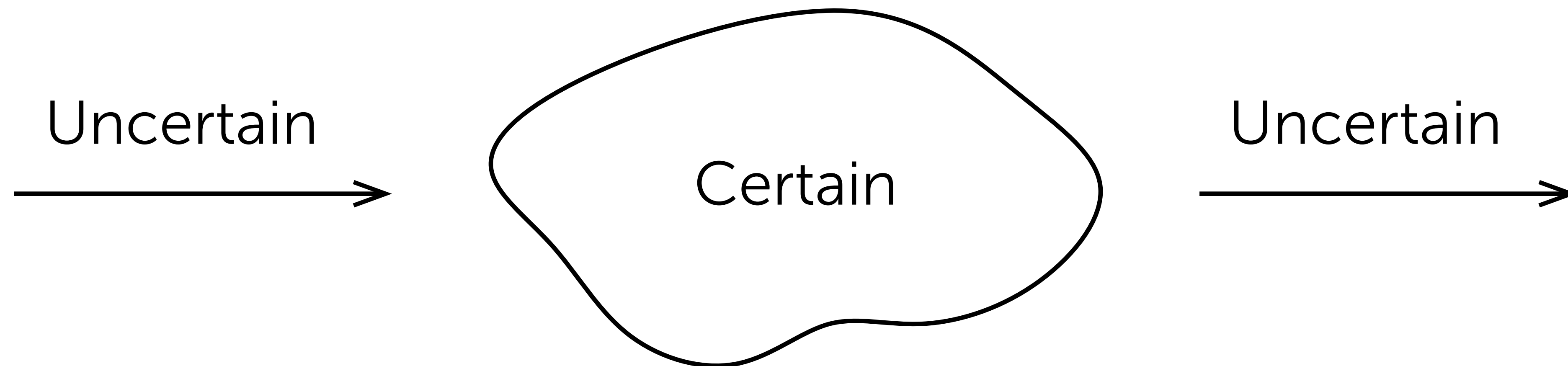
Our Solution



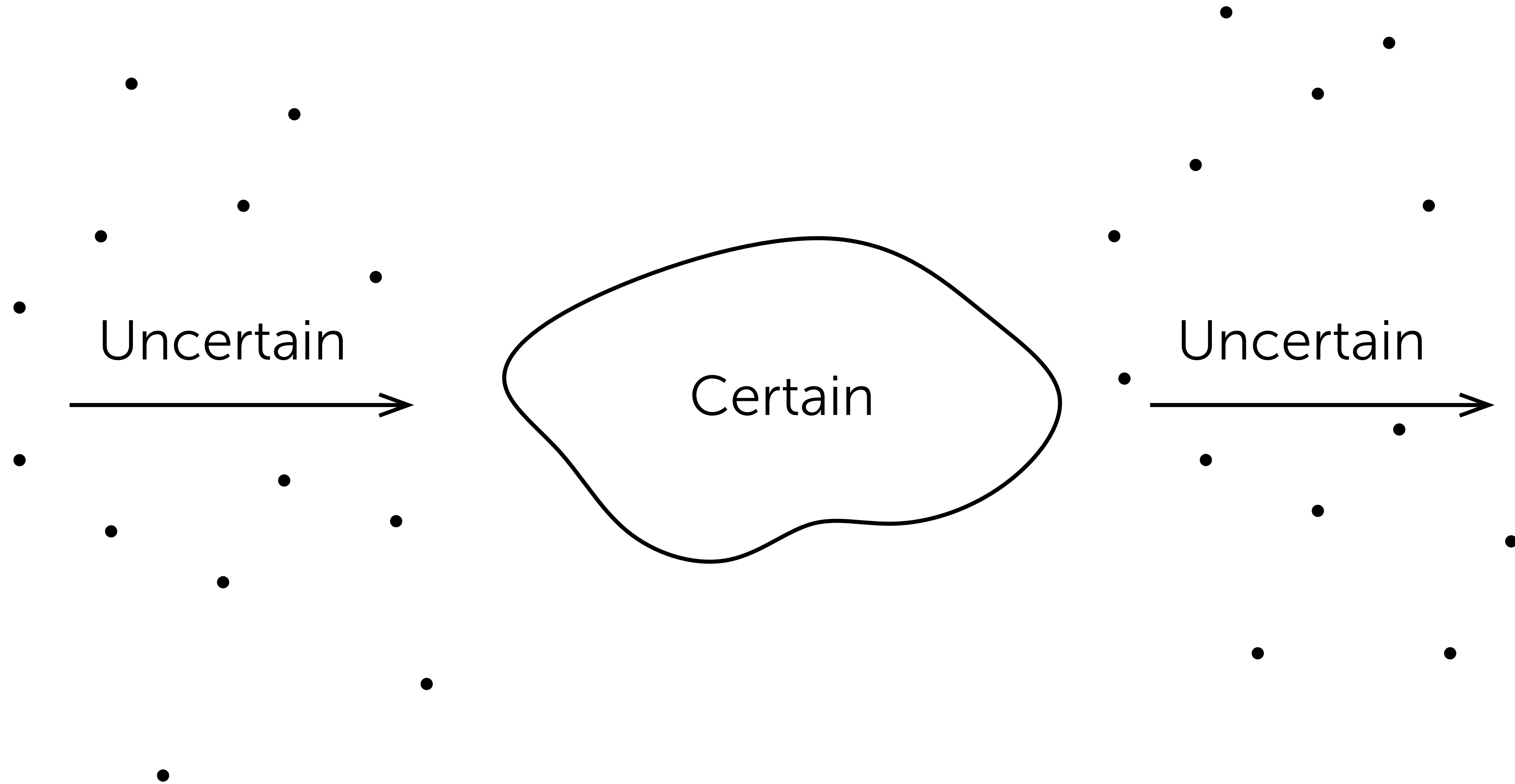
Uncertainty Quantification



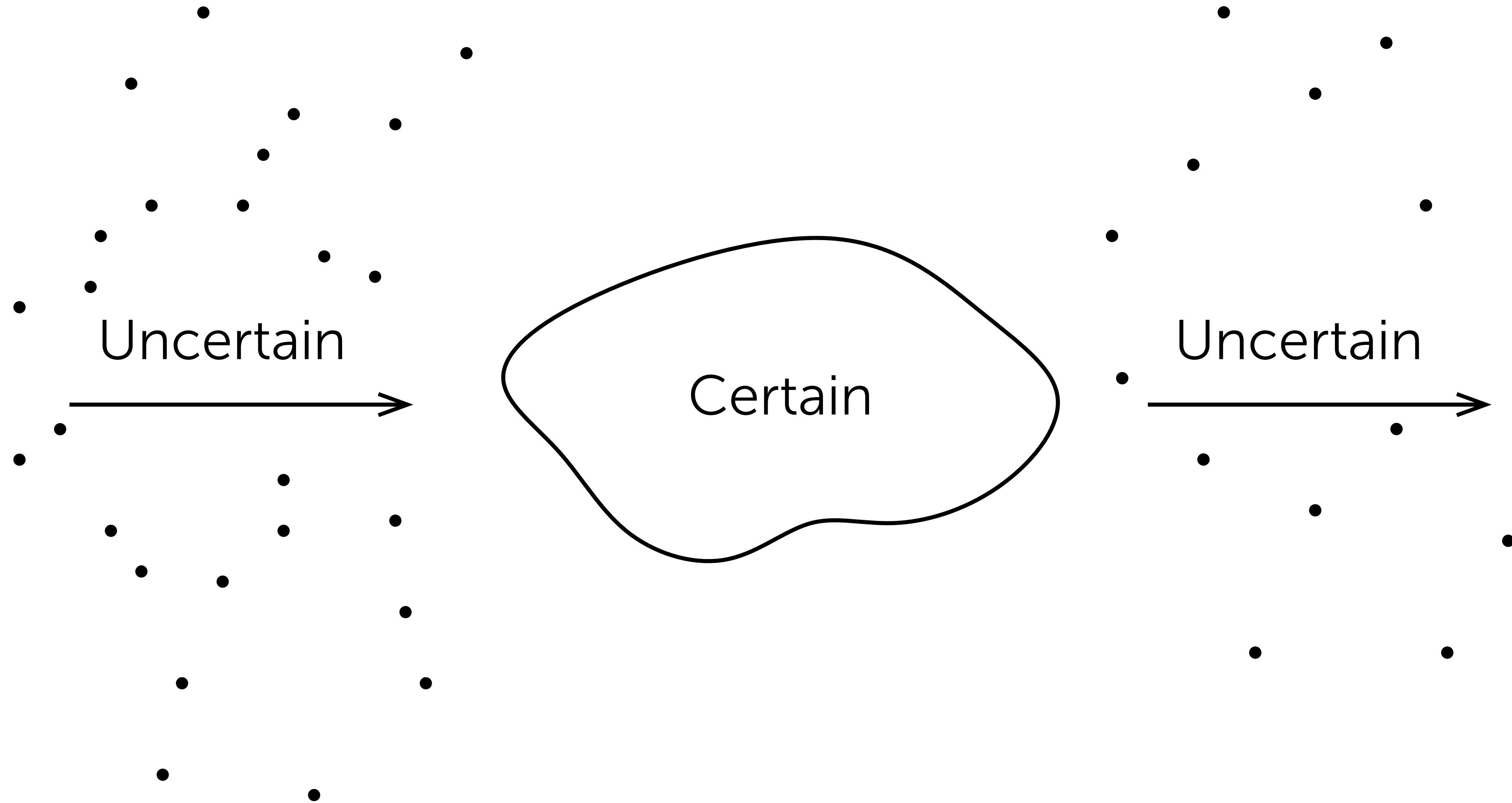
Uncertainty Quantification



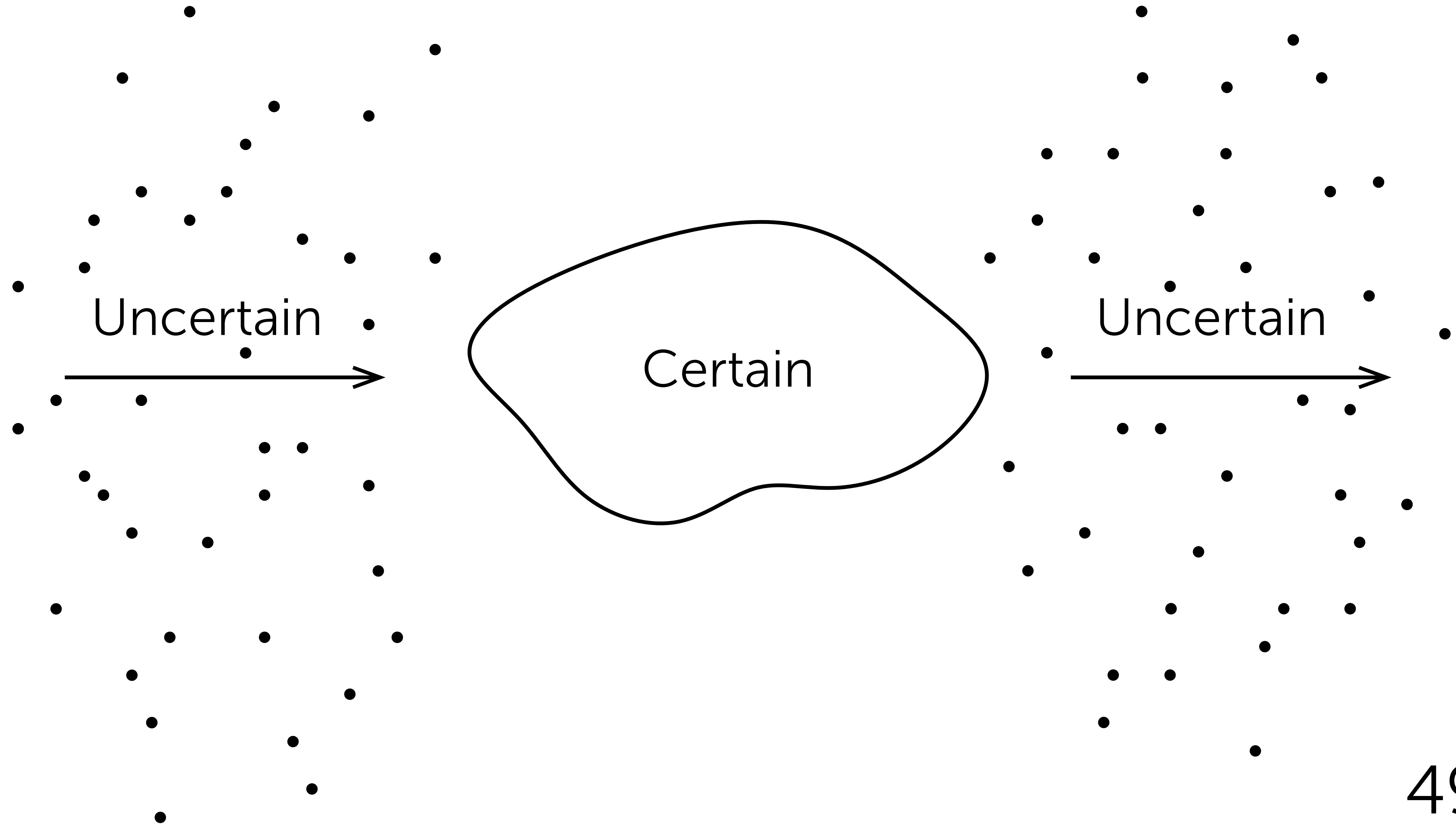
Monte Carlo



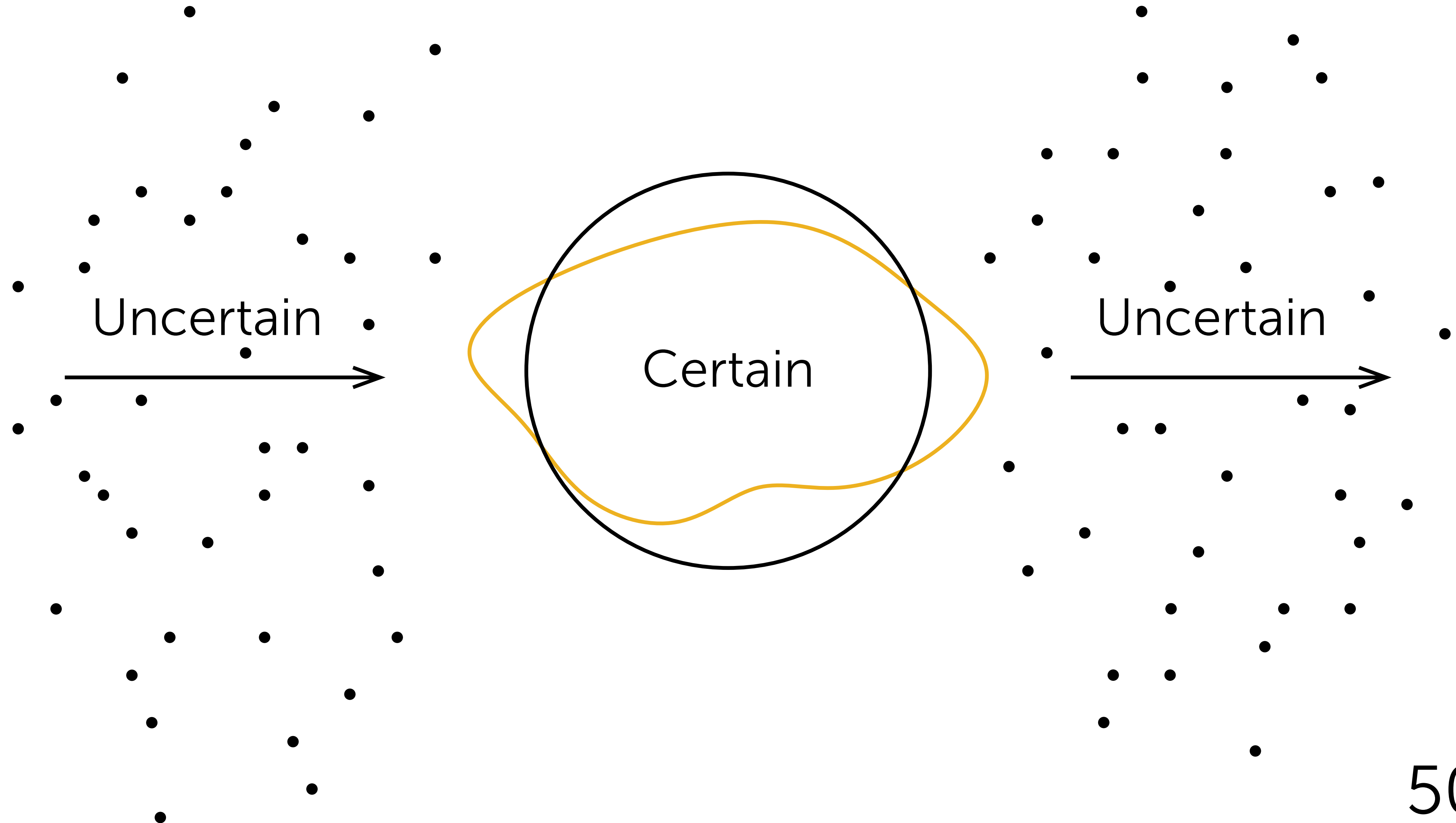
Monte Carlo



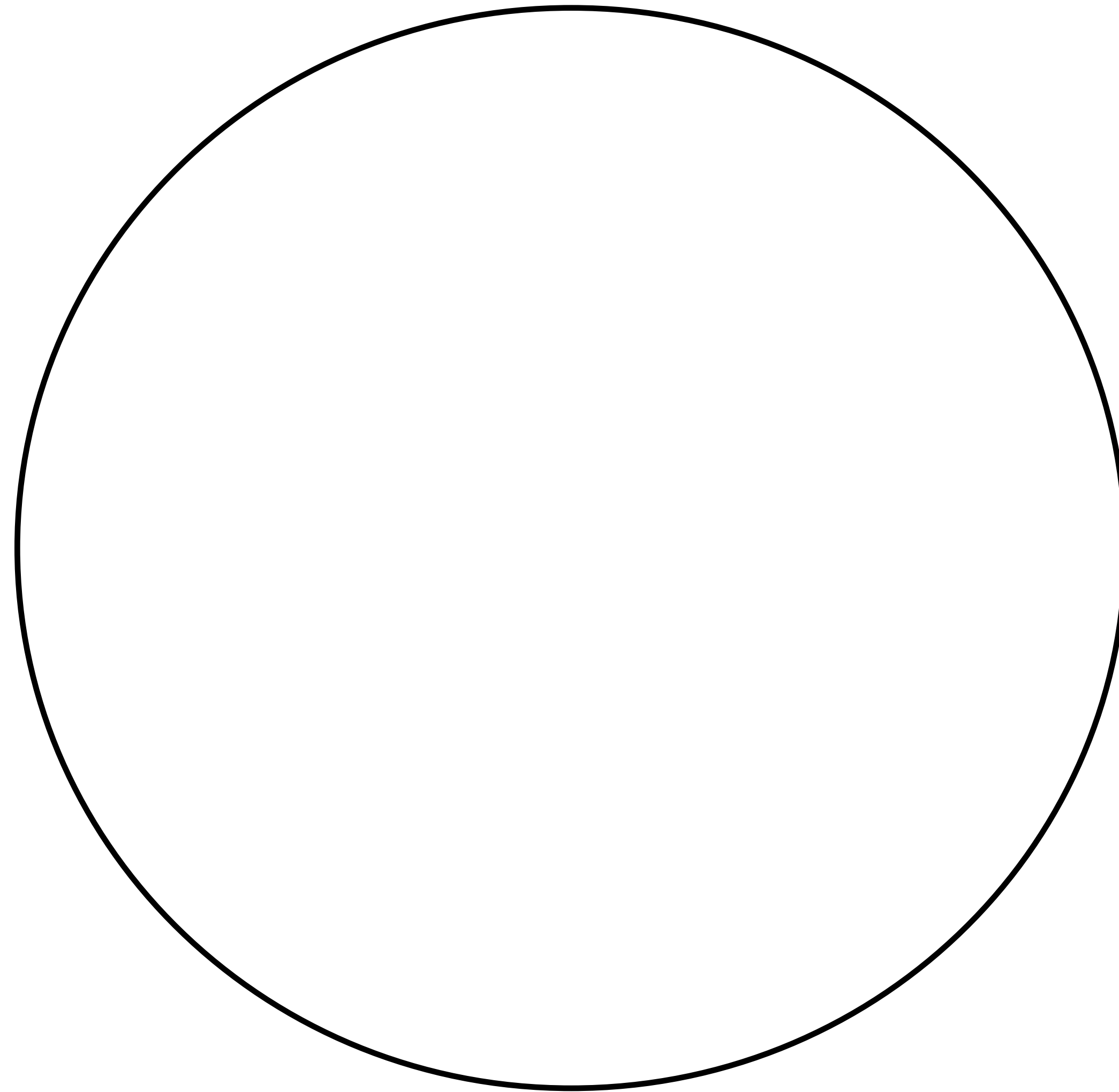
Monte Carlo



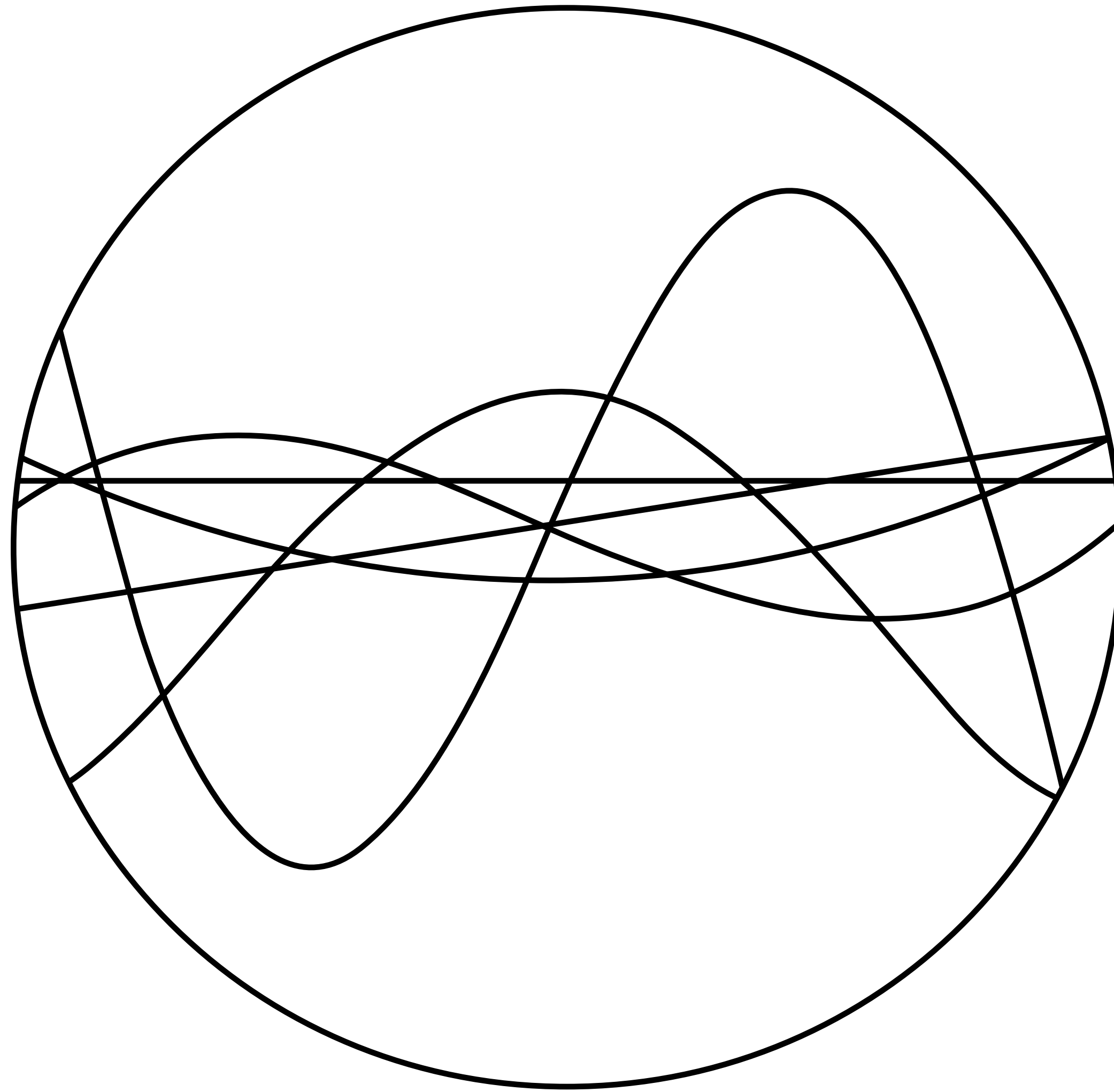
Our Solution



Polynomial Chaos



Polynomial Chaos

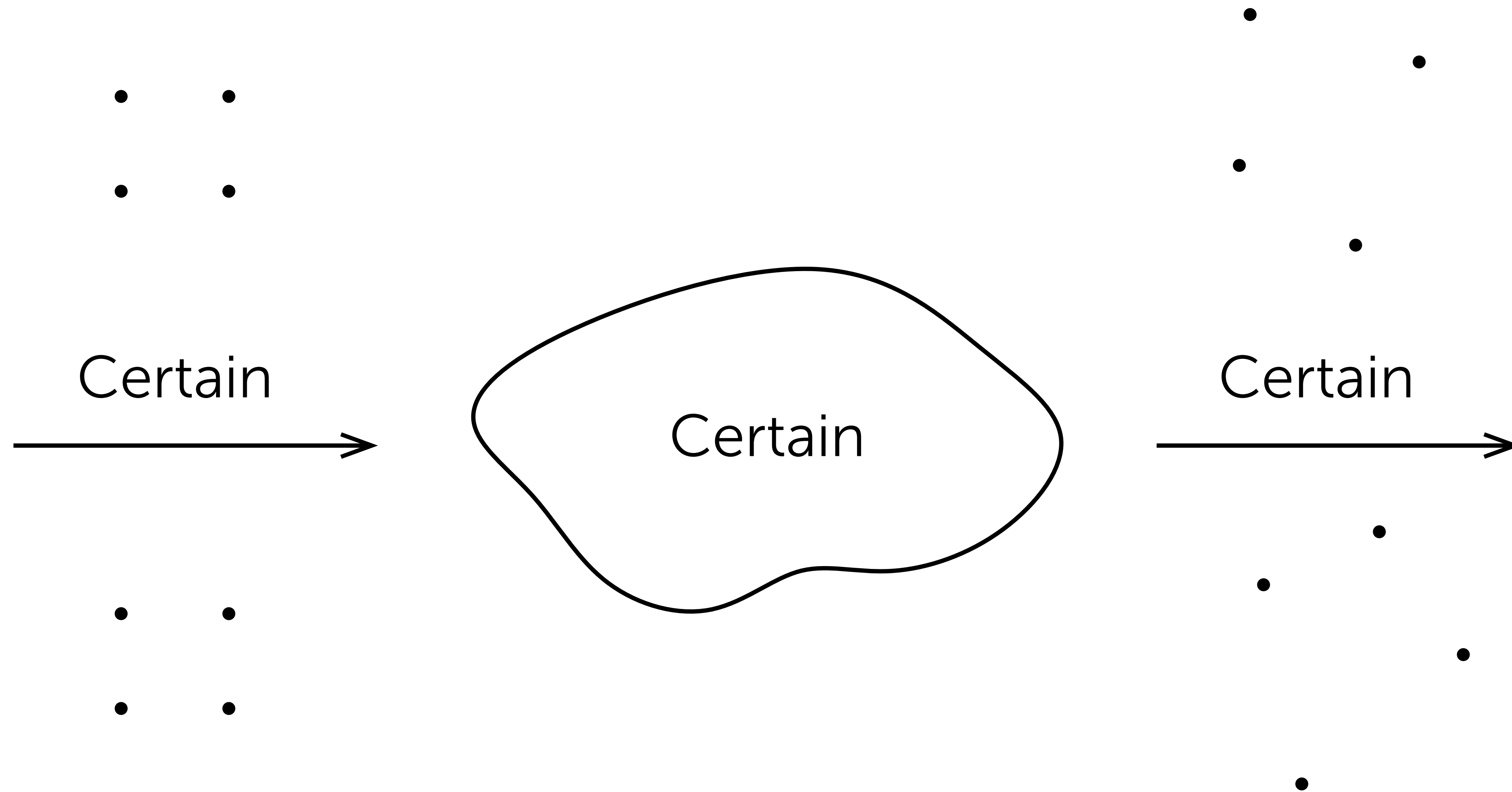


Polynomial Chaos

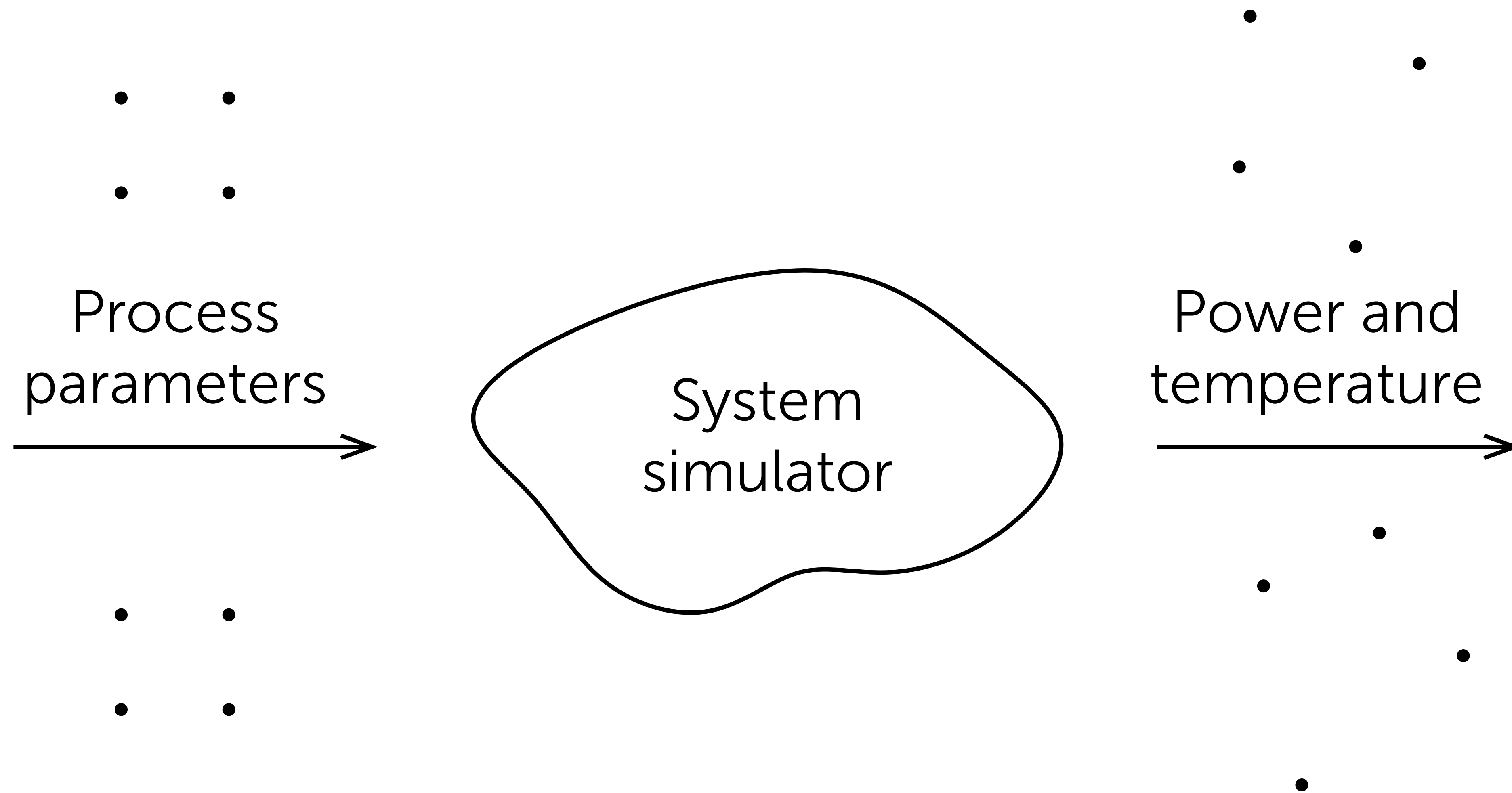
$$\theta(\xi) \approx \sum_{\alpha} \hat{\theta}_{\alpha} \psi_{\alpha}(\xi)$$

$$\hat{\theta}_{\alpha} = \langle \theta, \psi_{\alpha} \rangle$$

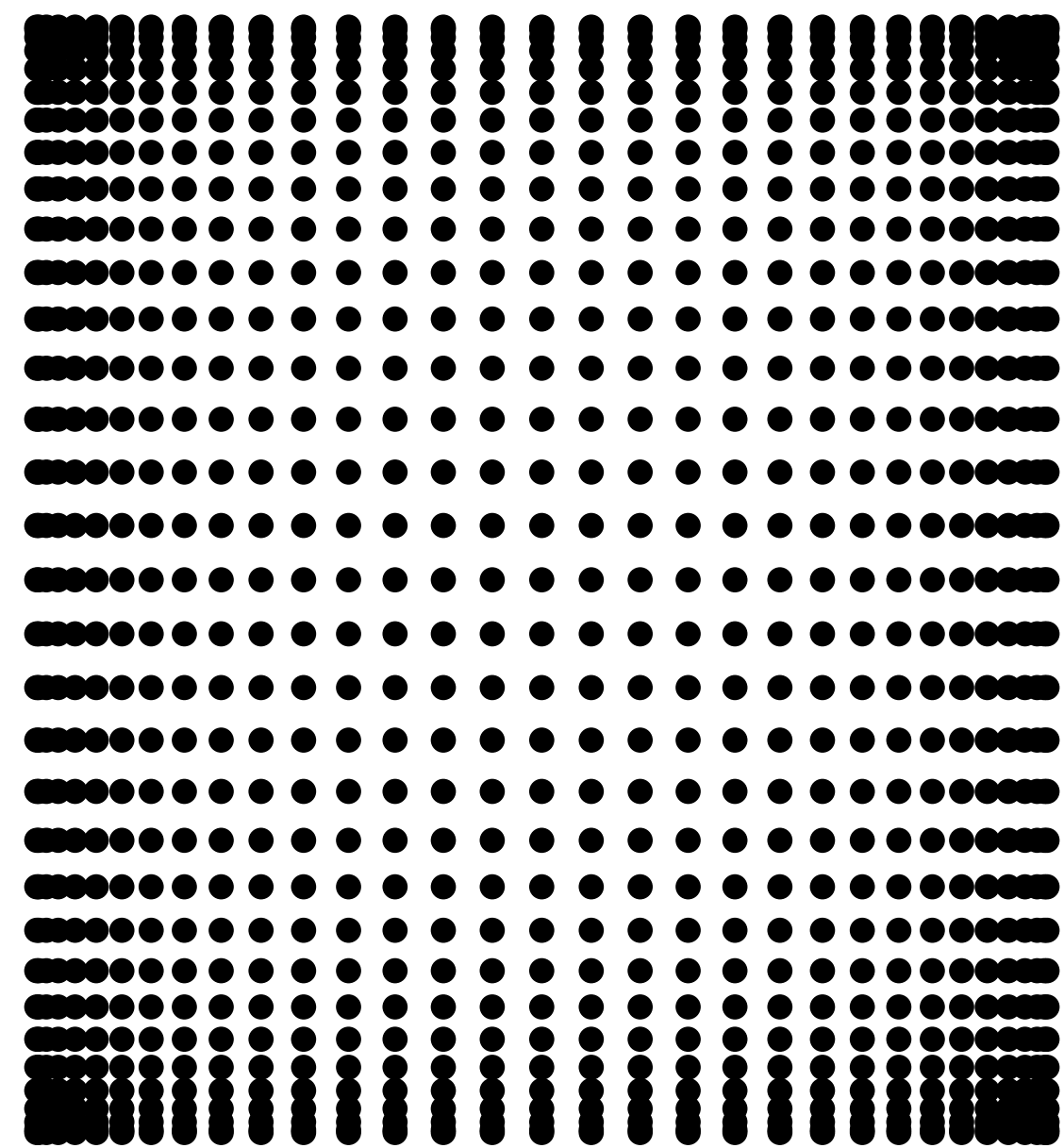
Quadratures



Power and Temperature

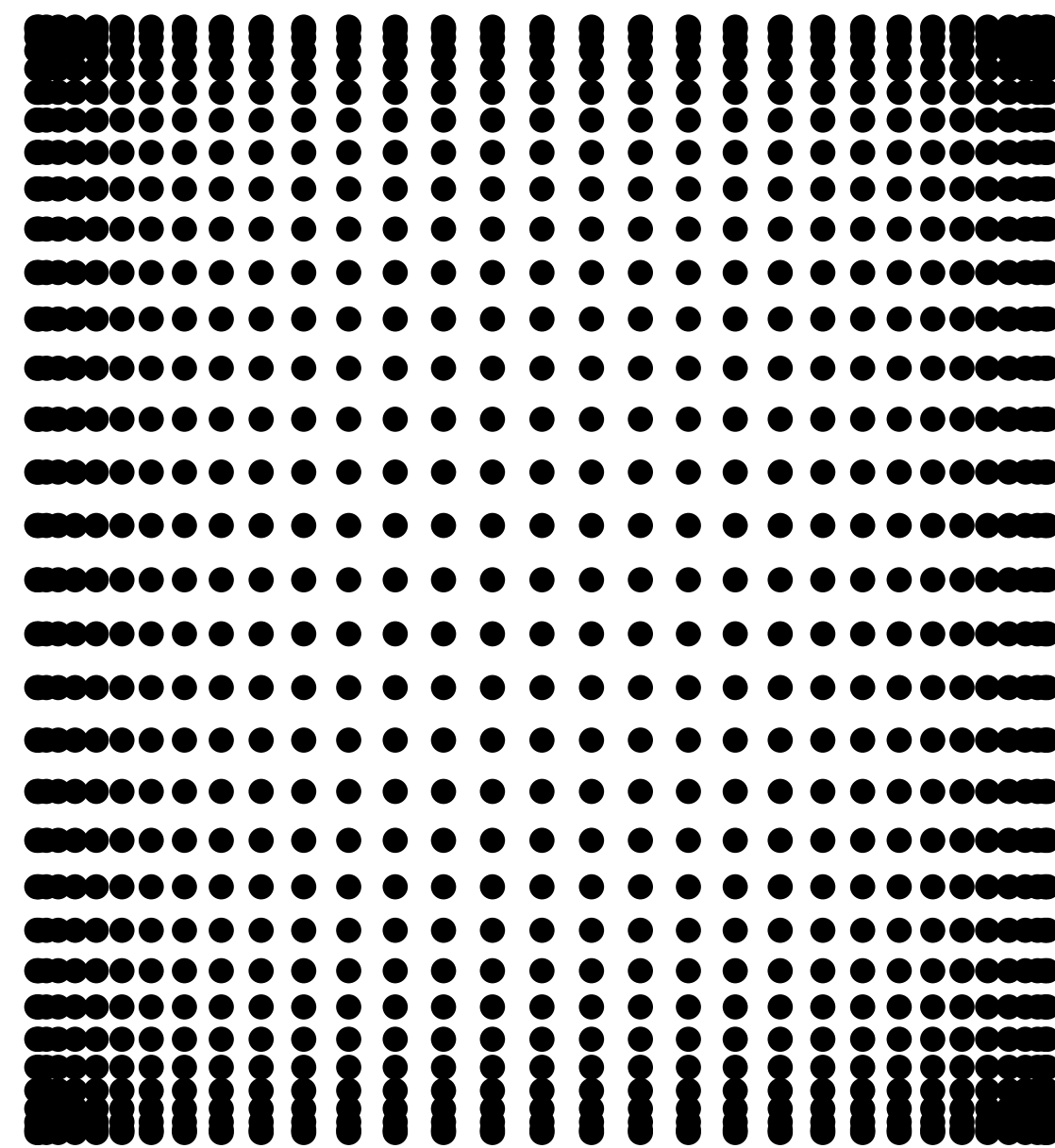


Quadratures

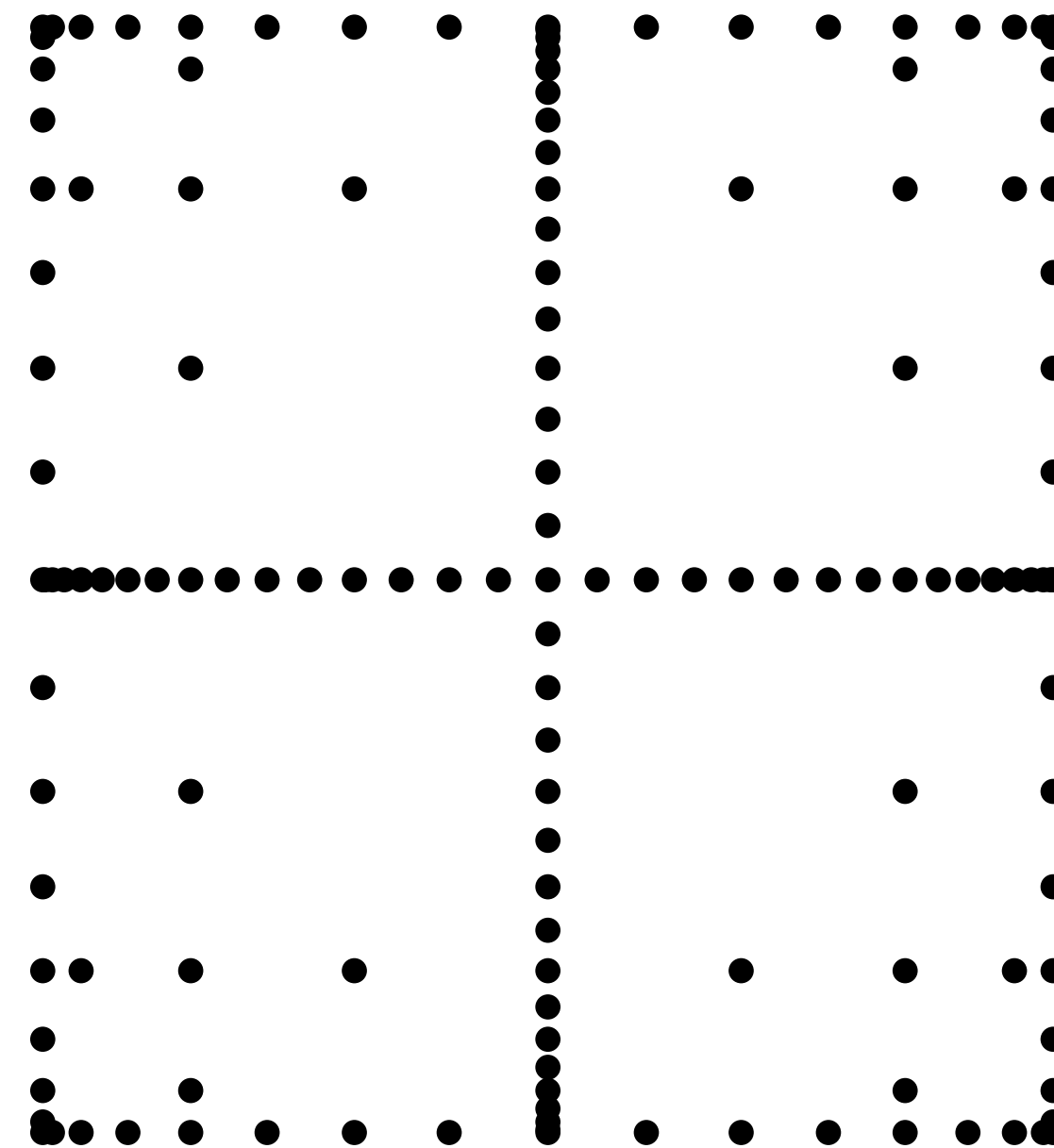


Tensor product

Quadratures



Tensor product



Sparse grid

Our Solution

- * Arbitrary probability distributions
- * Spatial correlations
- * Leakage-temperature interplay

Outline



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Probabilistic Analysis of Power and
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Temperature-Centric Reliability Analysis
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Our Goal

Given:

- * Multiprocessor system
- * Process variation

Perform:

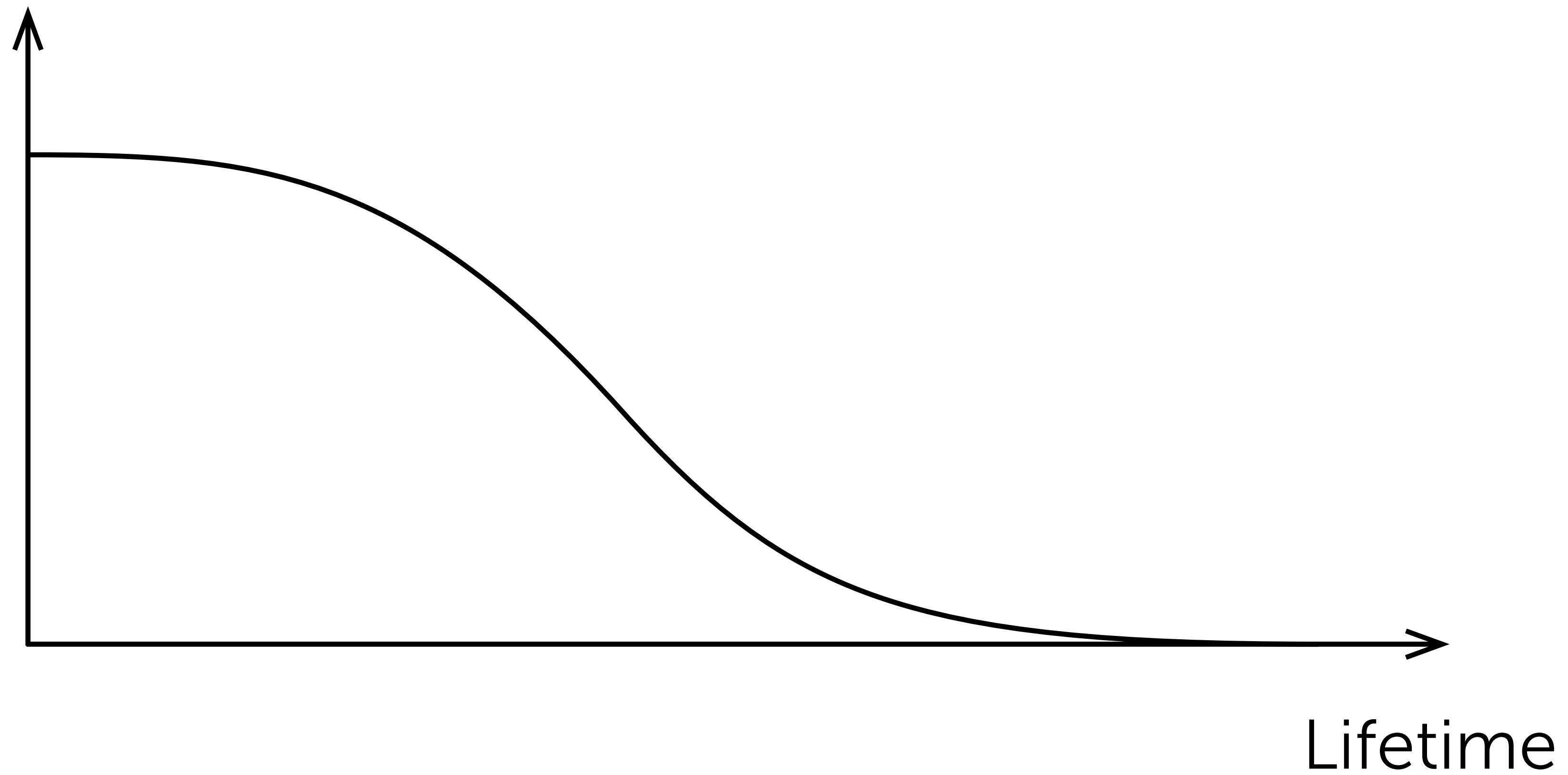
- * Reliability analysis

Such that:

- * Accurate and fast

Reliability Analysis

Survival function



Survival Function

$$R(t|\theta)$$

Survival Function

$$R(t|\theta)$$

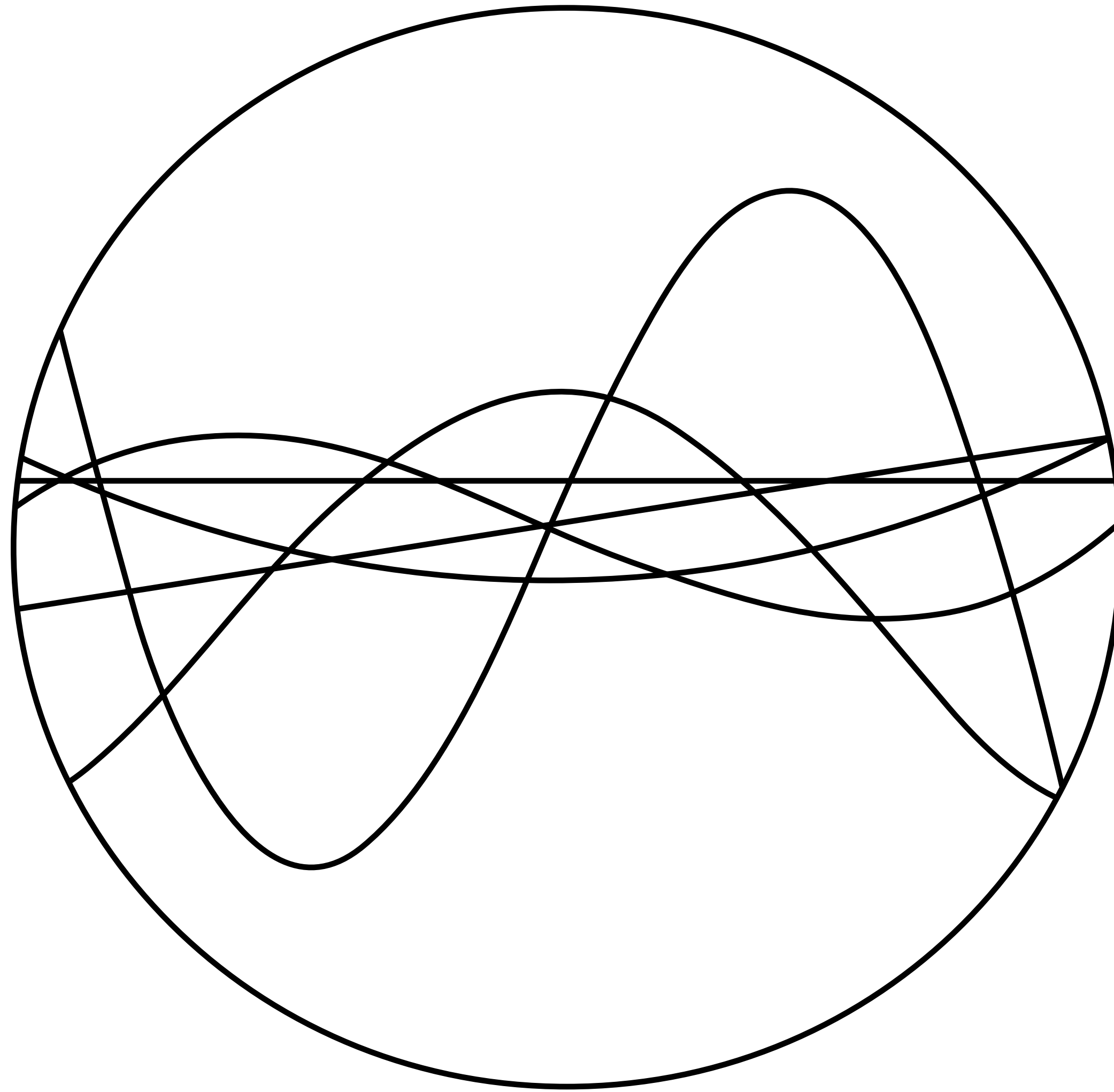
$$\theta = (\theta_1, \theta_2, \dots)$$

$$\theta_i = f_i(\text{system simulation})$$

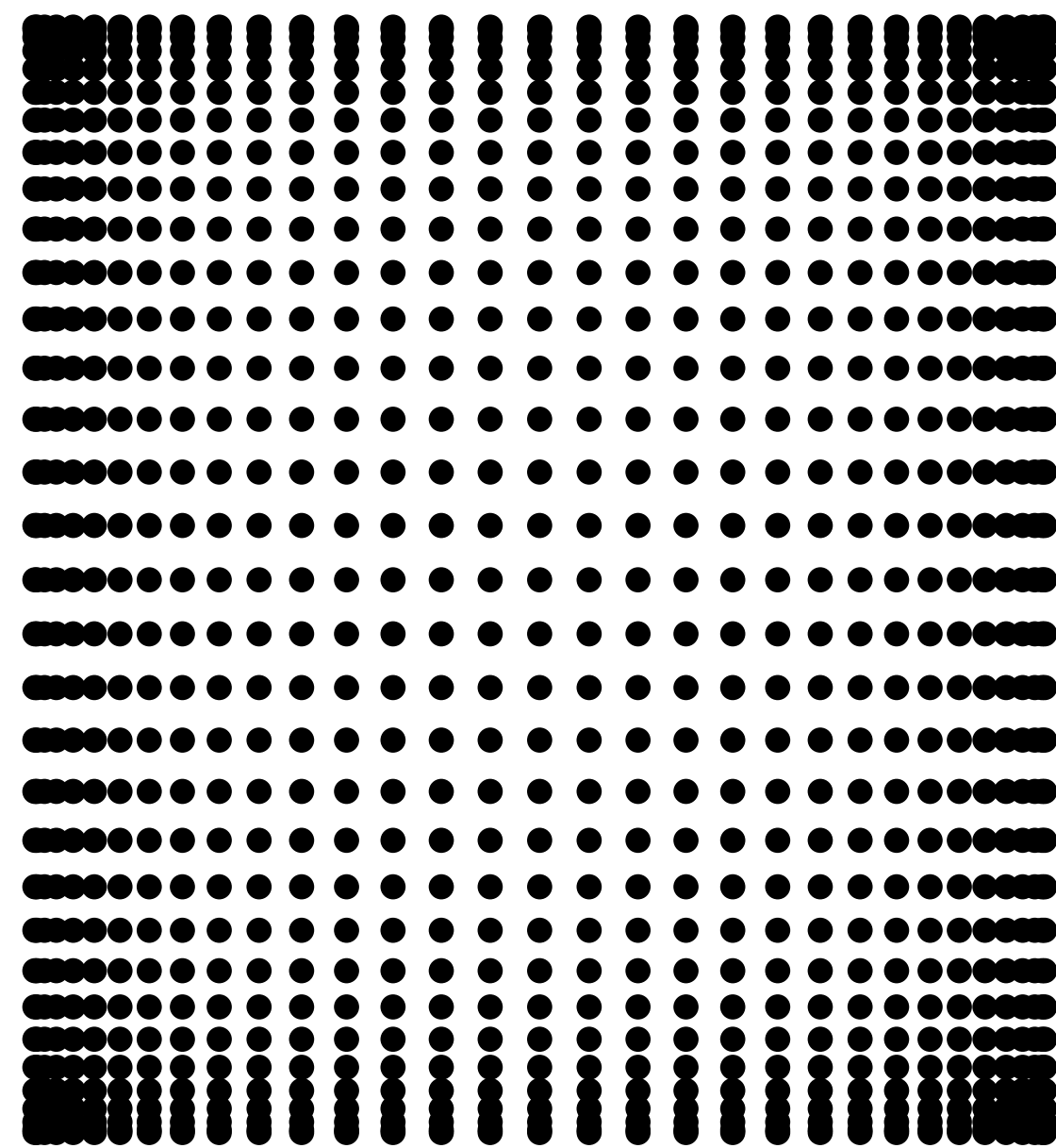
Our Solution

$$\theta_i(\xi) \approx \sum_{\alpha} \hat{\theta}_{i,\alpha} \psi_{\alpha}(\xi)$$

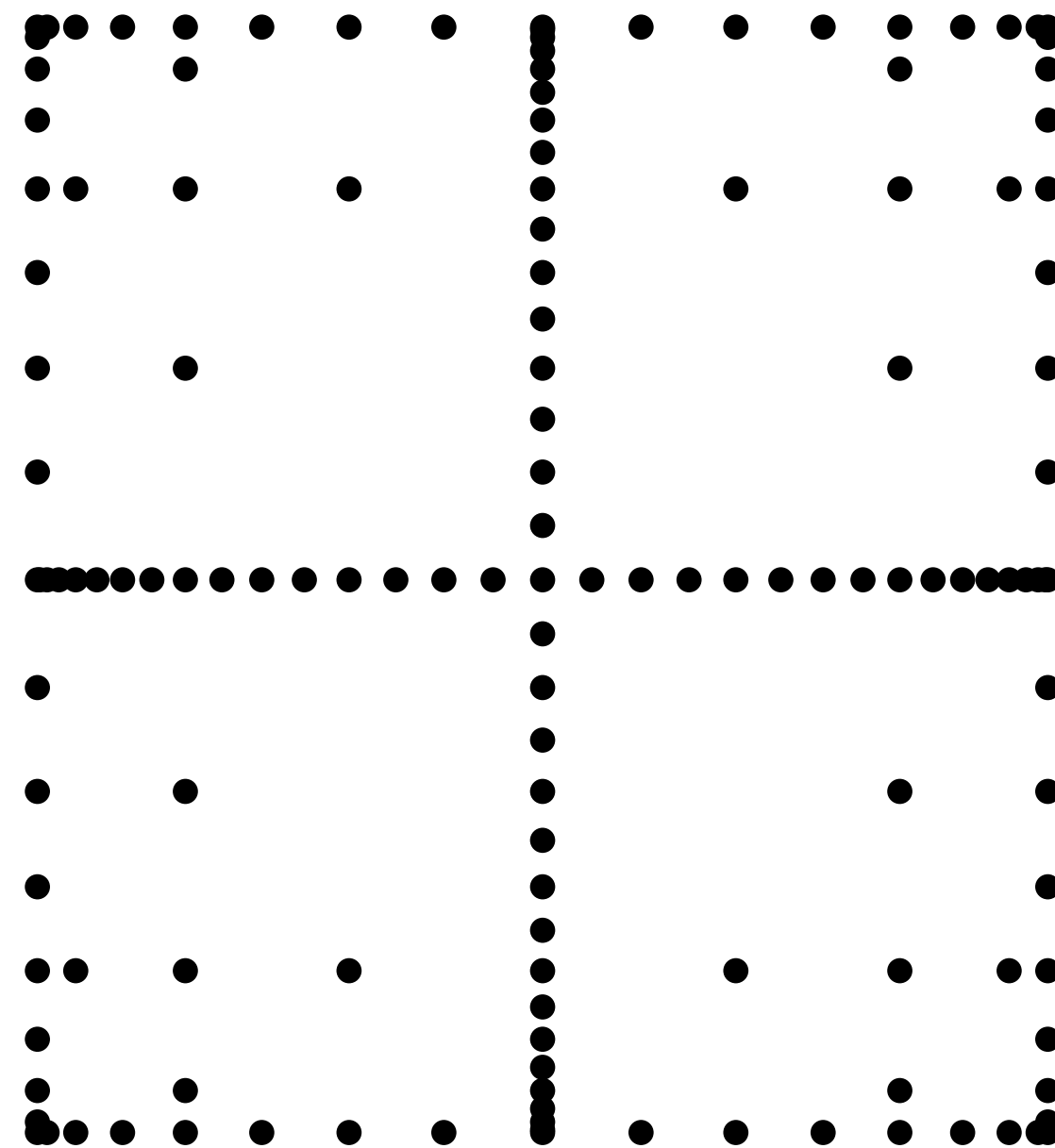
Polynomial Chaos



Quadratures

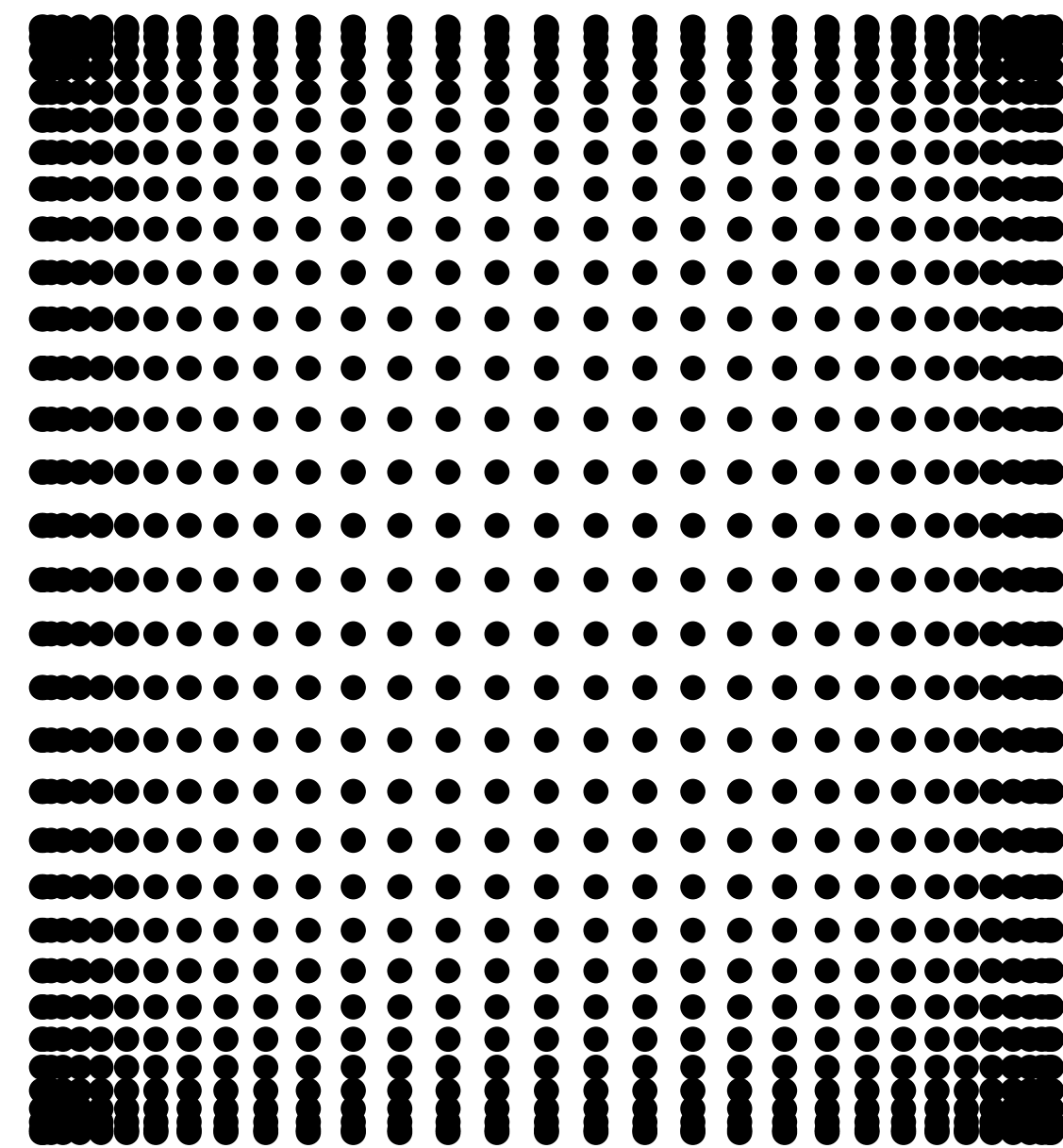


Tensor product

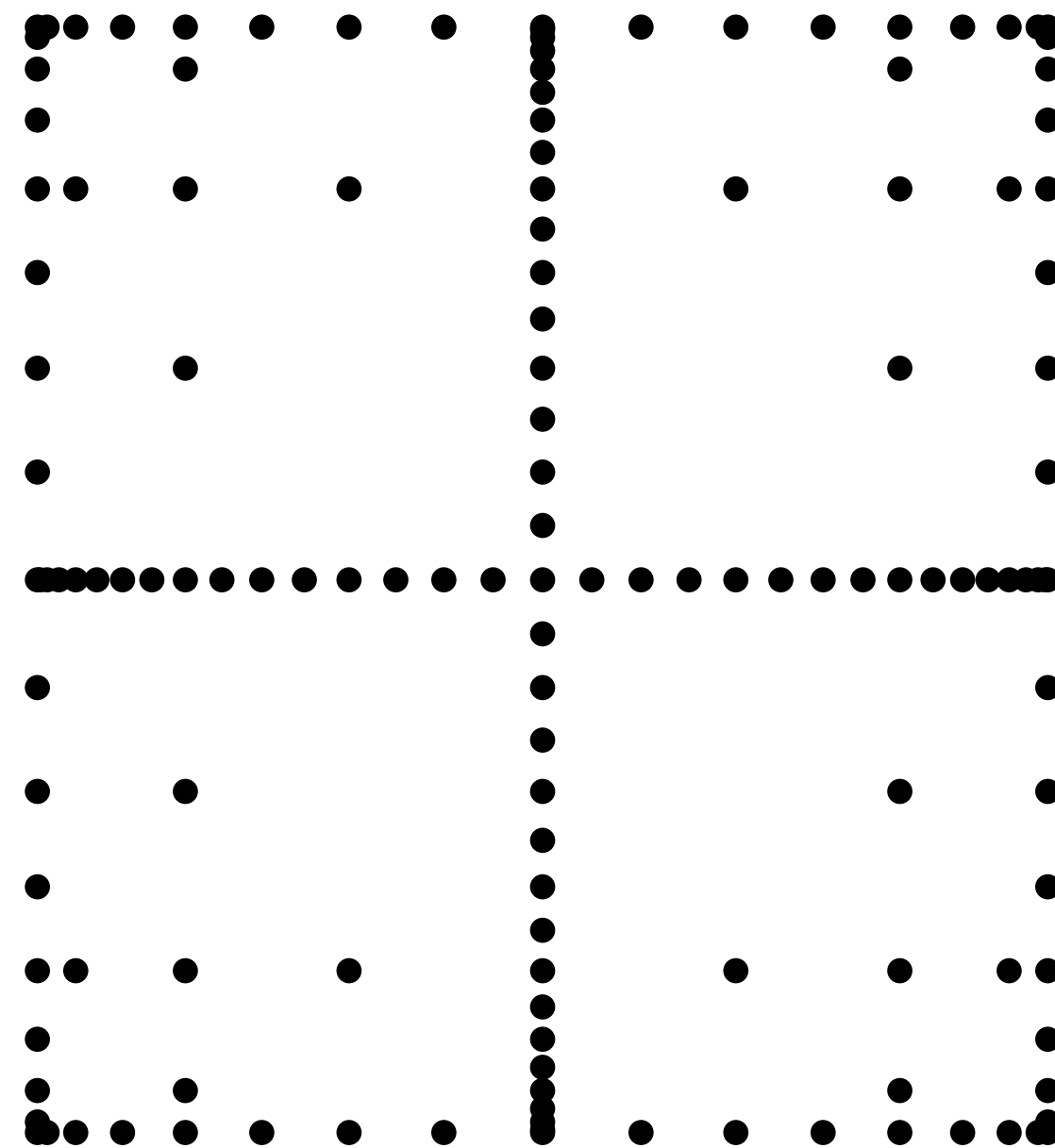


Sparse grid

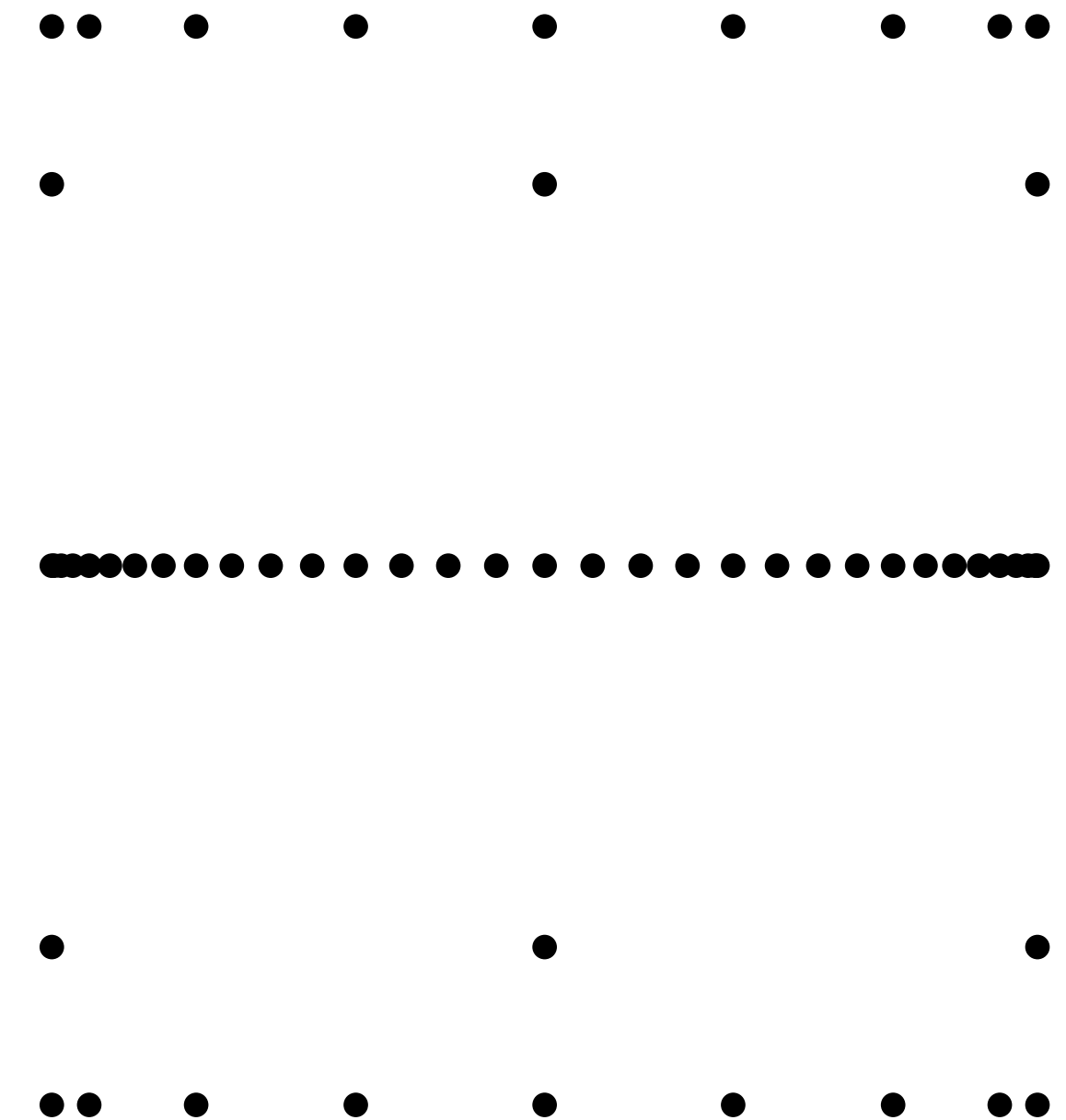
Quadratures



Tensor product



Sparse grid



Sparser grid

Reliability Optimization

- * Thermal-cyclic fatigue
- * Dynamic steady-state temperature analysis

Our Goal

Given:

- * Multiprocessor system
- * Process variation

Find:

- * Schedule

Such that:

- * ...

Our Goal

Such that:

- * Expected energy minimized
- * Probability of burn constrained
- * Probability of wear-out constrained



Thank you! Questions?

<https://users.ece.cmu.edu/~iukhov>